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Platform Flash In-System Programmable Configuration PROMS

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Preliminary Product Specification

Features

- In-System Programmable PROMs for Configuration of Xilinx FPGAs
- Low-Power Advanced CMOS NOR FLASH Process
- Endurance of 20,000 Program/Erase Cycles
- Operation over Full Industrial Temperature Range (-40°C to +85°C)
- IEEE Standard 1149.1/1532 Boundary-Scan (JTAG) Support for Programming, Prototyping, and Testing
- JTAG Command Initiation of Standard FPGA Configuration
- Cascadable for Storing Longer or Multiple Bitstreams
- Dedicated Boundary-Scan (JTAG) I/O Power Supply (V_{CCI})
- I/O Pins Compatible with Voltage Levels Ranging From 1.5V to 3.3V
- Design Support Using the Xilinx Alliance ISE and Foundation ISE Series Software Packages

- XCF01S/XCF02S/XCF04S
 - 3.3V supply voltage
 - Serial FPGA configuration interface (up to 33 MHz)
 - Available in small-footprint VO20 and VOG20 packages.
- XCF08P/XCF16P/XCF32P
 - 1.8V supply voltage
 - Serial or parallel FPGA configuration interface (up to 33 MHz)
 - Available in small-footprint VO48, VOG48, FS48, and FSG48 packages
 - Design revision technology enables storing and accessing multiple design revisions for configuration
 - Built-in data decompressor compatible with Xilinx advanced compression technology

Table 1: Platform Flash PROM Features

	Density	V _{CCINT}	V _{CCO} Range	V _{CCJ} Range	Packages	JTAG ISP Programming	Serial Config.	Parallel Config.	Design Revisioning	Compression
XCF01S	1 Mbit	3.3V	1.8V - 3.3V	2.5V - 3.3V	VO20/VOG20	1			N	1007.
XCF02S	2 Mbit	3.3V	1.8V - 3.3V	2.5V - 3.3V	VO20/VOG20	COL	1			TOON C
XCF04S	4 Mbit	3.3V	1.8V - 3.3V	2.5V - 3.3V	VO20/VOG20	7 (1)	1			1.100
XCF08P	8 Mbit	1.8V	1.5V - 3.3V	2.5V - 3.3V	VO48/VOG48 FS48/FSG48	NOW	1	1	1	104
XCF16P	16 Mbit	1.8V	1.5V - 3.3V	2.5V - 3.3V	VO48/VOG48 FS48/FSG48	1/0	1	1	1	111
XCF32P	32 Mbit	1.8V	1.5V - 3.3V	2.5V - 3.3V	VO48/VOG48 FS48/FSG48	100 1 .CC	1	V	1	

Description

Xilinx introduces the Platform Flash series of in-system programmable configuration PROMs. Available in 1 to 32 Megabit (Mbit) densities, these PROMs provide an easy-to-use, cost-effective, and reprogrammable method for storing large Xilinx FPGA configuration bitstreams. The Platform Flash PROM series includes both the 3.3V XCFxxS PROM and the 1.8V XCFxxP PROM. The XCFxxS version includes 4-Mbit, 2-Mbit, and 1-Mbit PROMs that

support Master Serial and Slave Serial FPGA configuration modes (Figure 1). The XCFxxP version includes 32-Mbit, 16-Mbit, and 8-Mbit PROMs that support Master Serial, Slave Serial, Master SelectMAP, and Slave SelectMAP FPGA configuration modes (Figure 2). A summary of the Platform Flash PROM family members and supported features is shown in Table 1.

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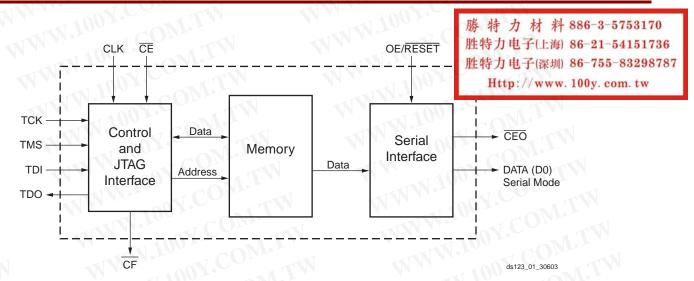


Figure 1: XCFxxS Platform Flash PROM Block Diagram

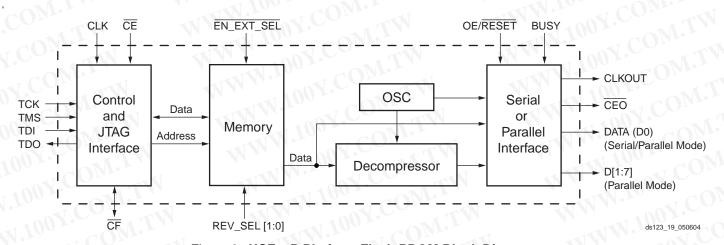


Figure 2: XCFxxP Platform Flash PROM Block Diagram

When the FPGA is in Master Serial mode, it generates a configuration clock that drives the PROM. With \overline{CF} High, a short access time after \overline{CE} and OE are enabled, data is available on the PROM DATA (D0) pin that is connected to the FPGA DIN pin. New data is available a short access time after each rising clock edge. The FPGA generates the appropriate number of clock pulses to complete the configuration.

When the FPGA is in Slave Serial mode, the PROM and the FPGA are both clocked by an external clock source, or optionally, for the XCFxxP PROM only, the PROM can be used to drive the FPGA's configuration clock.

The XCFxxP version of the Platform Flash PROM also supports Master SelectMAP and Slave SelectMAP (or Slave Parallel) FPGA configuration modes. When the FPGA is in Master SelectMAP mode, the FPGA generates a configuration clock that drives the PROM. When the FPGA is in Slave SelectMAP Mode, either an external oscillator generates the configuration clock that drives the PROM and the FPGA, or optionally, the XCFxxP PROM can be used to drive the FPGA's configuration clock. With BUSY Low and

CF High, after CE and OE are enabled, data is available on the PROMs DATA (D0-D7) pins. New data is available a short access time after each rising clock edge. The data is clocked into the FPGA on the following rising edge of the CCLK. A free-running oscillator can be used in the Slave Parallel /Slave SelecMAP mode.

The XCFxxP version of the Platform Flash PROM provides additional advanced features. A built-in data decompressor supports utilizing compressed PROM files, and design revisioning allows multiple design revisions to be stored on a single PROM or stored across several PROMs. For design revisioning, external pins or internal control bits are used to select the active design revision.

Multiple Platform Flash PROM devices can be cascaded to support the larger configuration files required when targeting larger FPGA devices or targeting multiple FPGAs daisy chained together. When utilizing the advanced features for the XCFxxP Platform Flash PROM, such as design revisioning, programming files which span cascaded PROM devices can only be created for cascaded chains containing only XCFxxP PROMs. If the advanced XCFxxP features are



not enabled, then the cascaded chain can include both XCFxxP and XCFxxS PROMs.

The Platform Flash PROMs are compatible with all of the existing FPGA device families. A reference list of Xilinx FPGAs and the respective compatible Platform Flash PROMs is given in Table 2. A list of Platform Flash PROMs and their capacities is given in Table 3.

Table 2: Xilinx FPGAs and Compatible Platform Flash PROMs

FPGA	Configuration Bitstream	Platform Flash PROM ⁽¹⁾
Virtex-4 LX		ON CO
XC4VLX15	4,765,185	XCF08P
XC4VLX25	7,819,520	XCF08P
XC4VLX40	12,259,328	XCF16P
XC4VLX60	17,717,248	XCF32P
XC4VLX80	23,290,624	XCF32P
XC4VLX100	30,711,296	XCF32P
XC4VLX160	40,346,624	XCF32P+XCF08P
XC4VLX200	48,722,432	XCF32P+XCF16P
Virtex-4 FX		100
XC4VFX12	4,765,184	XCF08P
XC4VFX20	7,242,240	XCF08P
XC4VFX40	13,550,336	XCF16P
XC4VFX60	21,002,496	XCF32P
XC4VFX100	33,065,024	XCF32P
XC4VFX140	47,856,512	XCF32P+XCF16P
Virtex-4 SX	O. T.	MAN
XC4VSX25	9,147,264	XCF16P
XC4VSX35	13,669,904	XCF16P
XC4VSX55	22,744,832	XCF32P
Virtex-II Pro X	COM	
XC2VPX20	8,214,560	XCF08P
XC2VPX70	26,098,976	XCF32P
Virtex-II Pro	01.	
XC2VP2	1,305,376	XCF02S
XC2VP4	3,006,496	XCF04S
XC2VP7	4,485,408	XCF08P
XC2VP20	8,214,560	XCF08P
XC2VP30	11,589,920	XCF16P
XC2VP40	15,868,192	XCF16P
XC2VP50	19,021,344	XCF32P
XC2VP70	26,098,976	XCF32P
XC2VP100	34,292,768	XCF32P ⁽²⁾
Virtex-II (3)	100 2	COM
XC2V40	360,096	XCF01S
XC2V80	635,296	XCF01S

Table 2: Xilinx FPGAs and Compatible Platform Flash PROMs (Continued)

FPGA	Configuration Bitstream	Platform Flash PROM ⁽¹⁾
XC2V250	1,697,184	XCF02S
XC2V500	2,761,888	XCF04S
XC2V1000	4,082,592	XCF04S
XC2V1500	5,659,296	XCF08P
XC2V2000	7,492,000	XCF08P
XC2V3000	10,494,368	XCF16P
XC2V4000	15,659,936	XCF16P
XC2V6000	21,849,504	XCF32P
XC2V8000	29,063,072	XCF32P
Virtex-E	-1XV 100	COM
XCV50E	630,048	XCF01S
XCV100E	863,840	XCF01S
XCV200E	1,442,016	XCF02S
XCV300E	1,875,648	XCF02S
XCV400E	2,693,440	XCF04S
XCV405E	3,430,400	XCF04S
XCV600E	3,961,632	XCF04S
XCV812E	6,519,648	XCF08P
XCV1000E	6,587,520	XCF08P
XCV1600E	8,308,992	XCF08P
XCV2000E	10,159,648	XCF16P
XCV2600E	12,922,336	XCF16P
XCV3200E	16,283,712	XCF16P
Virtex		WW. T. C
XCV50	559,200	XCF01S
XCV100	781,216	XCF01S
XCV150	1,040,096	XCF01S
XCV200	1,335,840	XCF02S
XCV300	1,751,808	XCF02S
XCV400	2,546,048	XCF04S
XCV600	3,607,968	XCF04S
XCV800	4,715,616	XCF08P
XCV1000	6,127,744	XCF08P
Spartan-3E	OMr.	
XC3S100E	581,344	XCF01S
XC3S250E	1,352,192	XCF02S
XC3S500E	2,267,136	XCF04S
XC3S1200E	3,832,320	XCF04S
XC3S1600E	5,957,760	XCF08P
Spartan-3L		
XC3S1000L	3,223,488	XCF04S
XC3S1500L	5,214,784	XCF08P
XC3S5000L	13,271,936	XCF16P



Table 2: Xilinx FPGAs and Compatible Platform Flash PROMs (Continued)

FPGA	Configuration Bitstream	Platform Flash PROM ⁽¹⁾
Spartan-3	WWW.	V.Co
XC3S50	439,264	XCF01S
XC3S200	1,047,616	XCF01S
XC3S400	1,699,136	XCF02S
XC3S1000	3,223,488	XCF04S
XC3S1500	5,214,784	XCF08P
XC3S2000	7,673,024	XCF08P
XC3S4000	11,316,864	XCF16P
XC3S5000	13,271,936	XCF16P
Spartan-IIE	N	×11001.
XC2S50E	630,048	XCF01S
XC2S100E	863,840	XCF01S
XC2S150E	1,134,496	XCF02S
XC2S200E	1,442,016	XCF02S
XC2S300E	1,875,648	XCF02S
XC2S400E	2,693,440	XCF04S
XC2S600E	3,961,632	XCF04S
Spartan-II		11/11
XC2S15	197,696	XCF01S
XC2S30	336,768	XCF01S
XC2S50	559,200	XCF01S
XC2S100	781,216	XCF01S
XC2S150	1,040,096	XCF01S
XC2S200	1,335,840	XCF02S

Notes

- If design revisioning or other advanced feature support is required, the XCFxxP can be used as an alternative to the XCF01S, XCF02S, or XCF04S.
- 2. Assumes compression used.
- The largest possible Virtex-II bitstream sizes are specified. Refer to the Virtex-II User Guide for information on bitgen options which affect bitstream size.

Table 3: Platform Flash PROM Capacity

Platform Flash PROM	Configuration Bits	Platform Flash PROM	Configuration Bits
XCF01S	1,048,576	XCF08P	8,388,608
XCF02S	2,097,152	XCF16P	16,777,216
XCF04S	4,194,304	XCF32P	33,554,432

Programming

In-System Programming

In-System Programmable PROMs can be programmed individually, or two or more can be daisy-chained together and programmed in-system via the standard 4-pin JTAG protocol as shown in Figure 3. In-system programming offers quick and efficient design iterations and eliminates unnecessary package handling or socketing of devices. The

programming data sequence is delivered to the device using either Xilinx iMPACT software and a Xilinx download cable, a third-party JTAG development system, a JTAG-compatible board tester, or a simple microprocessor interface that emulates the JTAG instruction sequence. The iMPACT software also outputs serial vector format (SVF) files for use with any tools that accept SVF format, including automatic test equipment. During in-system programming, the CEO output is driven High. All other outputs are held in a high-impedance state or held at clamp levels during in-system programming. In-system programming is fully supported across the recommended operating voltage and temperature ranges.

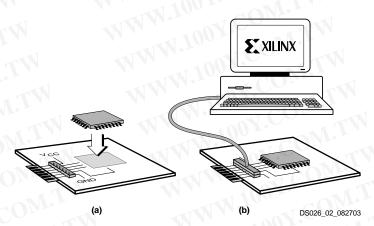


Figure 3: JTAG In-System Programming Operation
(a) Solder Device to PCB
(b) Program Using Download Cable

OE/RESET

The 1/2/4 Mbit XCFxxS Platform Flash PROMs in-system programming algorithm results in issuance of an internal device reset that causes OE/RESET to pulse Low.

External Programming

Xilinx reprogrammable PROMs can also be programmed by the Xilinx MultiPRO Desktop Tool or a third-party device programmer. This provides the added flexibility of using pre-programmed devices with an in-system programmable option for future enhancements and design changes.

Reliability and Endurance

Xilinx in-system programmable products provide a guaranteed endurance level of 20,000 in-system program/erase cycles and a minimum data retention of 20 years. Each device meets all functional, performance, and data retention specifications within this endurance limit.

Design Security

The Xilinx in-system programmable Platform Flash PROM devices incorporate advanced data security features to fully protect the FPGA programming data against unauthorized reading via JTAG. The XCFxxP PROMs can also be pro-



grammed to prevent inadvertent writing via JTAG. Table 4 and Table 5 show the security settings available for the XCFxxS PROM and XCFxxP PROM, respectively.

Read Protection

The read protect security bit can be set by the user to prevent the internal programming pattern from being read or copied via JTAG. Read protection does not prevent write operations. For the XCFxxS PROM, the read protect security bit is set for the entire device, and resetting the read protect security bit requires erasing the entire device. For the XCFxxP PROM the read protect security bit can be set for individual design revisions, and resetting the read protect bit requires erasing the particular design revision.

Write Protection

The XCFxxP PROM device also allows the user to write protect (or lock) a particular design revision to prevent inadvertent erase or program operations. Once set, the write protect security bit for an individual design revision must be reset (using the UNLOCK command followed by ISC_ERASE command) before an erase or program operation can be performed.

Table 4: XCFxxS Device Data Security Options

Read Protect	Read/Verify Inhibited	Program Inhibited	Erase Inhibited
Reset (default)	100	M	TW
Set	1	M.Co.	WT

Table 5: XCFxxP Design Revision Data Security Options

Read Protect	Write Protect	Read/Verify Inhibited	Program Inhibited	Erase Inhibited
Reset (default)	Reset (default)	WT	MAL	OY.
Reset (default)	Set		V	OV.CV
Set	Reset (default)	0		COMP
Set	Set	1.1	V	100 × 40M

IEEE 1149.1 Boundary-Scan (JTAG)

The Platform Flash PROM family is IEEE Standard 1532 in-system programming compatible, and is fully compliant with the IEEE Std. 1149.1 Boundary-Scan, also known as JTAG, which is a subset of IEEE Std. 1532 Boundary-Scan. A Test Access Port (TAP) and registers are provided to support all required boundary scan instructions, as well as many of the optional instructions specified by IEEE Std. 1149.1. In addition, the JTAG interface is used to implement in-system programming (ISP) to facilitate configuration, erasure, and verification operations on the Platform Flash PROM device. Table 6 lists the required and optional boundary-scan instructions supported in the Platform Flash PROMs. Refer to the IEEE Std. 1149.1 specification for a complete description of boundary-scan architecture and the required and optional instructions.

Instruction Register

The Instruction Register (IR) for the Platform Flash PROM is connected between TDI and TDO during an instruction scan sequence. In preparation for an instruction scan sequence, the instruction register is parallel loaded with a fixed instruction capture pattern. This pattern is shifted out onto TDO (LSB first), while an instruction is shifted into the instruction register from TDI.

XCFxxS Instruction Register (8 bits wide)

The Instruction Register (IR) for the XCFxxS PROM is eight bits wide and is connected between TDI and TDO during an instruction scan sequence. The detailed composition of the instruction capture pattern is illustrated in Figure 4. The instruction capture pattern shifted out of the XCFxxS device includes IR[7:0]. IR[7:5] are reserved bits and are set to a logic "0". The ISC Status field, IR[4], contains logic "1" if the device is currently in In-System Configuration (ISC) mode; otherwise, it contains logic "0". The Security field, IR[3], contains logic "1" if the device has been programmed with the security option turned on; otherwise, it contains logic "0". IR[2] is unused, and is set to '0'. The remaining bits IR[1:0] are set to '01' as defined by IEEE Std. 1149.1.

XCFxxP Instruction Register (16 bits wide)

The Instruction Register (IR) for the XCFxxP PROM is sixteen bits wide and is connected between TDI and TDO during an instruction scan sequence. The detailed composition of the instruction capture pattern is illustrated in Figure 5.

The instruction capture pattern shifted out of the XCFxxP device includes IR[15:0]. IR[15:9] are reserved bits and are set to a logic "0". The ISC Error field, IR[8:7], contains a "10" when an ISC operation is a success; otherwise a "01" when an In-System Configuration (ISC) operation fails. The Erase/Program (ER/PROG) Error field, IR[6:5], contains a "10" when an erase or program operation is a success; oth-



erwise a "01" when an erase or program operation fails. The Erase/Program (ER/PROG) Status field, IR[4], contains a logic "1" when the device is busy performing an erase or programming operation; otherwise, it contains a logic "0". The ISC Status field, IR[3], contains logic "1" if the device is currently in In-System Configuration (ISC) mode; otherwise,

it contains logic "0". The DONE field, IR[2], contains logic "1" if the sampled design revision has been successfully programmed; otherwise, a logic "0" indicates incomplete programming. The remaining bits IR[1:0] are set to '01' as defined by IEEE Std. 1149.1

Table 6: Platform Flash PROM Boundary Scan Instructions

Boundary-Scan Command	XCFxxS IR[7:0] (hex)	XCFxxP IR[15:0] (hex)	Instruction Description
Required Instructions	100X.Co	TTV	WW. 1100Y.
BYPASS	FF	FFFF	Enables BYPASS
SAMPLE/PRELOAD	01	0001	Enables boundary-scan SAMPLE/PRELOAD operation
EXTEST	00	0000	Enables boundary-scan EXTEST operation
Optional Instructions	W. TOOK	COTTY	WW. 100x. Car.TW
CLAMP	FA	00FA	Enables boundary-scan CLAMP operation
HIGHZ	FC	00FC	Places all outputs in high-impedance state simultaneously
IDCODE	FE	OOFE	Enables shifting out 32-bit IDCODE
USERCODE	FD	00FD	Enables shifting out 32-bit USERCODE
Platform Flash PROM Specific Instructions	MAIN W	TOON: COM!	IN WWW.1007.COM
CONFIG	EE	OOEE	Initiates FPGA configuration by pulsing \overline{CF} pin Low once. (For the XCFxxP this command also resets the selected design revision based on either the external REV_SEL[1:0] pins or on the internal design revision selection bits.) ⁽¹⁾

Notes:

^{1.} For more information see Initiating FPGA Configuration.

TDI	IR[7:5]	IR[4]	IR[3]	IR[2]	IR[1:0]	→ TDO
	Reserved	ISC Status	Security	0	0 1	→ IDO

Figure 4: XCFxxS Instruction Capture Values Loaded into IR as part of an Instruction Scan Sequence

	IR[15:9]	IR[8:7]	IR[6:5]	IR[4]	IR[3]	IR[2]	IR[1:0]	100
TDI →	Reserved	ISC Error	ER/PROG Error	ER/PROG Status	ISC Status	DONE	01	→ TDO

Figure 5: XCFxxP Instruction Capture Values Loaded into IR as part of an Instruction Scan Sequence

Boundary Scan Register

The boundary-scan register is used to control and observe the state of the device pins during the EXTEST, SAM-PLE/PRELOAD, and CLAMP instructions. Each output pin on the Platform Flash PROM has two register stages which contribute to the boundary-scan register, while each input pin has only one register stage. The bidirectional pins have a total of three register stages which contribute to the boundary-scan register. For each output pin, the register

stage nearest to TDI controls and observes the output state, and the second stage closest to TDO controls and observes the High-Z enable state of the output pin. For each input pin, a single register stage controls and observes the input state of the pin. The bidirectional pin combines the three bits, the input stage bit is first, followed by the output stage bit and finally the output enable stage bit. The output enable stage bit is closest to TDO.



See the XCFxxS/XCFxxP Pin Names and Descriptions Tables in the **Pinouts and Pin Descriptions** section for the boundary-scan bit order for all connected device pins, or see the appropriate BSDL file for the complete boundary-scan bit order description under the "attribute BOUNDARY_REGISTER" section in the BSDL file. The bit assigned to boundary-scan cell "0" is the LSB in the boundary-scan register, and is the register bit closest to TDO.

Identification Registers

IDCODE Register

The IDCODE is a fixed, vendor-assigned value that is used to electrically identify the manufacturer and type of the device being addressed. The IDCODE register is 32 bits wide. The IDCODE register can be shifted out for examination by using the IDCODE instruction. The IDCODE is available to any other system component via JTAG. Table 7 lists the IDCODE register values for the Platform Flash PROMs.

The IDCODE register has the following binary format:

vvvv:ffff:ffff:aaaa:aaaa:cccc:cccc:cccl

where

v = the die version number

f = the PROM family code

a = the specific Platform Flash PROM product ID

c = the Xilinx manufacturer's ID

The LSB of the IDCODE register is always read as logic "1" as defined by IEEE Std. 1149.1.

Table 7: IDCODES Assigned to Platform Flash PROMs

Device	IDCODE ⁽¹⁾ (hex)	
XCF01S	<v>5044093</v>	
XCF02S	<v>5045093</v>	
XCF04S	<v>5046093</v>	
XCF08P	<v>5057093</v>	
XCF16P	<v>5058093</v>	
XCF32P	<v>5059093</v>	

Notes:

 The <v> in the IDCODE field represents the device's revision code (in hex), and may vary.

USERCODE Register

The USERCODE instruction gives access to a 32-bit user programmable scratch pad typically used to supply information about the device's programmed contents. By using the USERCODE instruction, a user-programmable identification code can be shifted out for examination. This code is loaded into the USERCODE register during programming of the Platform Flash PROM. If the device is blank or was not loaded during programming, the USERCODE register contains FFFFFFFFh.

Customer Code Register

For the XCFxxP Platform Flash PROM, in addition to the USERCODE, a unique 32-byte Customer Code can be assigned to each design revision enabled for the PROM. The Customer Code is set during programming, and is typically used to supply information about the design revision contents. A private JTAG instruction is required to read the Customer Code. If the PROM is blank, or the Customer Code for the selected design revision was not loaded during programming, or if the particular design revision is erased, the Customer Code will contain all ones.

Platform Flash PROM TAP Characteristics

The Platform Flash PROM family performs both in-system programming and IEEE 1149.1 boundary-scan (JTAG) testing via a single 4-wire Test Access Port (TAP). This simplifies system designs and allows standard Automatic Test Equipment to perform both functions. The AC characteristics of the Platform Flash PROM TAP are described as follows.

TAP Timing

Figure 6 shows the timing relationships of the TAP signals. These TAP timing characteristics are identical for both boundary-scan and ISP operations.

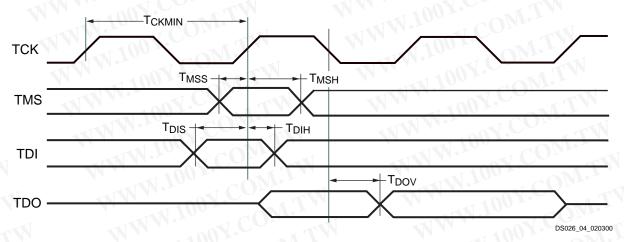


Figure 6: Test Access Port Timing

TAP AC Parameters

Table 8 shows the timing parameters for the TAP waveforms shown in Figure 6.

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Table 8: Test Access Port Timing Parameter
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Symbol	Description		Min	Max	Units
T _{CKMIN}	TCK minimum clock period when V _{CCJ} = 2.5V or 3.3V	WW	100	M.C.	ns
T _{MSS}	TMS setup time when V _{CCJ} = 2.5V or 3.3V	-37	10	<u>.</u>	ns
T _{MSH}	TMS hold time when V _{CCJ} = 2.5V or 3.3V		25	100.	ns
T _{DIS}	TDI setup time when V _{CCJ} = 2.5V or 3.3V	N.	10	10-07	ns
T _{DIH}	TDI hold time when $V_{CCJ} = 2.5V$ or $3.3V$		25	-00	ns
T _{DOV}	TDO valid delay when V _{CCJ} = 2.5V or 3.3V			30	ns

Additional Features for the XCFxxP Internal Oscillator

The 8/16/32 Mbit XCFxxP Platform Flash PROMs include an optional internal oscillator which can be used to drive the CLKOUT and DATA pins on FPGA configuration interface. The internal oscillator can be enabled during device programming, and can be set to either the default frequency or to a slower frequency (AC Characteristics Over Operating Conditions When Cascading).

CLKOUT

The 8/16/32 Mbit XCFxxP Platform Flash PROMs include the programmable option to enable the CLKOUT signal which allows the PROM to provide a source synchronous clock aligned to the data on the configuration interface. The CLKOUT signal is derived from one of two clock sources: the CLK input pin or the internal oscillator. The input clock source is selected during the PROM programming sequence. Output data is available on the rising edge of CLKOUT.

The CLKOUT signal is enabled during programming, and is active when CE is Low and OE/RESET is High. When disabled, the CLKOUT pin is put into a high-impedance state and should be pulled High externally to provide a known state.

When cascading Platform Flash PROMs with CLKOUT enabled, after completing it's data transfer, the first PROM disables CLKOUT and releases the $\overline{\text{CEO}}$ pin enabling the next PROM in the PROM chain. The next PROM will begin driving the CLKOUT signal once that PROM is enabled and data is available for transfer.

During high-speed parallel configuration without compression, the FPGA drives the BUSY signal on the configuration interface. When BUSY is asserted High, the PROMs internal address counter stops incrementing, and the current data value is held on the data outputs. While BUSY is High, the PROM will continue driving the CLKOUT signal to the FPGA, clocking the FPGA's configuration logic. When the FPGA deasserts BUSY, indicating that it is ready to receive additional configuration data, the PROM will begin driving new data onto the configuration interface.



Decompression

The 8/16/32 Mbit XCFxxP Platform Flash PROMs include a built-in data decompressor compatible with Xilinx advanced compression technology. Compressed Platform Flash PROM files are created from the target FPGA bitstream(s) using the iMPACT software. Only Slave Serial and Slave SelectMAP (parallel) configuration modes are supported for FPGA configuration when using a XCFxxP PROM programmed with a compressed bitstream. Compression rates will vary depending on several factors, including the target device family and the target design contents.

The decompression option is enabled during the PROM programming sequence. The PROM decompresses the stored data before driving both clock and data onto the FPGA's configuration interface. If Decompression is enabled, then the Platform Flash clock output pin (CLK-

OUT) must be used as the clock signal for the configuration interface, driving the target FPGA's configuration clock input pin (CCLK). Either the PROM's CLK input pin or the internal oscillator must be selected as the source for CLK-OUT. Any target FPGA connected to the PROM must operate as slave in the configuration chain, with the configuration mode set to Slave Serial mode or Slave SelectMap (parallel) mode.

When decompression is enabled, the CLKOUT signal becomes a controlled clock output with a reduced maximum frequency. When decompressed data is not ready, the CLKOUT pin is put into a high-Z state and must be pulled High externally to provide a known state.

The BUSY input is automatically disabled when decompression is enabled.

Design Revisioning

Design Revisioning allows the user to create up to four unique design revisions on a single PROM or stored across multiple cascaded PROMs. Design Revisioning is supported for the 8/16/32 Mbit XCFxxP Platform Flash PROMs in both serial and parallel modes. Design Revisioning can be used with compressed PROM files, and also when the CLKOUT feature is enabled. The PROM programming files along with the revision information files (.cfi) are created using the iMPACT software. The .cfi file is required to enable design revision programming in iMPACT.

A single design revision is composed of from 1 to n 8-Mbit memory blocks. If a single design revision contains less than 8 Mbits of data, then the remaining space is padded with all ones. A larger design revision can span several 8-Mbit memory blocks, and any space remaining in the last 8-Mbit memory block is padded with all ones.

- A single 32-Mbit PROM contains four 8-Mbit memory blocks, and can therefore store up to four separate design revisions: one 32-Mbit design revision, two 16-Mbit design revisions, three 8-Mbit design revisions, four 8-Mbit design revisions, and so on.
- Because of the 8-Mbit minimum size requirement for each revision, a single 16-Mbit PROM can only store up to two separate design revisions: one 16-Mbit design revision, one 8-Mbit design revision, or two 8-Mbit design revisions.
- A single 8-Mbit PROM can store only one 8-Mbit design revision.

Larger design revisions can be split over several cascaded PROMs. For example, two 32-Mbit PROMs can store up to four separate design revisions: one 64-Mbit design revision, two 32-Mbit design revisions, three 16-Mbit design revisions, four 16-Mbit design revisions, and so on. When cas-

cading one 16-Mbit PROM and one 8-Mbit PROM, there are 24 Mbits of available space, and therefore up to three separate design revisions can be stored: one 24-Mbit design revision, two 8-Mbit design revisions, or three 8-Mbit design revisions.

See Figure 7 for a few basic examples of how multiple revisions can be stored. The design revision partitioning is handled automatically during file generation in iMPACT.

During the PROM file creation, each design revision is assigned a revision number:

Revision 0 = '00'

Revision 1 = '01'

Revision 2 = '10'

Revision 3 = '11'

After programming the Platform Flash PROM with a set of design revisions, a particular design revision can be selected using the external REV_SEL[1:0] pins or using the internal programmable design revision control bits. The EN_EXT_SEL pin determines if the external pins or internal bits are used to select the design revision. When EN_EXT_SEL is Low, design revision selection is controlled by the external Revision Select pins, REV_SEL[1:0]. When EN_EXT_SEL is High, design revision selection is controlled by the internal programmable Revision Select control bits. During power up, the design revision selection inputs (pins or control bits) are sampled internally. After power up, when CE is asserted (Low) enabling the PROM inputs, the design revision selection inputs are sampled again after the rising edge of the CF pulse. The data from the selected design revision is then presented on the FPGA configuration interface.

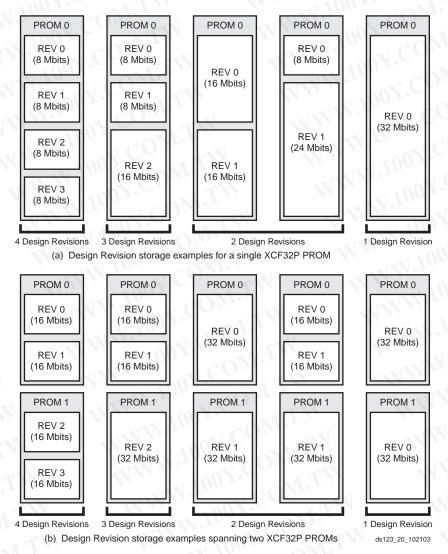


Figure 7: Design Revision Storage Examples

勝 特 力 材 料 886-3-5753170 胜特力电子(上海) 86-21-54151736 胜特力电子(深圳) 86-755-83298787 Http://www.100y.com.tw

PROM to FPGA Configuration Mode and Connections Summary

The FPGA's I/O, logical functions, and internal interconnections are established by the configuration data contained in the FPGA's bitstream. The bitstream is loaded into the FPGA either automatically upon power up, or on command, depending on the state of the FPGA's mode pins. Xilinx Platform Flash PROMs are designed to download directly to the FPGA configuration interface. FPGA configuration modes which are supported by the XCFxxS Platform Flash PROMs include: Master Serial and Slave Serial. FPGA configuration modes which are supported by the XCFxxP Platform Flash PROMs include: Master Serial, Slave Serial, Master SelectMAP, and Slave SelectMAP. Below is a short summary of the supported FPGA configuration modes. See the respective FPGA data sheet for device configuration details, including which configuration modes are supported by the targeted FPGA device.

FPGA Master Serial Mode

In Master Serial mode, the FPGA automatically loads the configuration bitstream in bit-serial form from external memory synchronized by the configuration clock (CCLK) generated by the FPGA. Upon power-up or reconfiguration, the FPGA's mode select pins are used to select the Master Serial configuration mode. Master Serial Mode provides a simple configuration interface. Only a serial data line, a clock line, and two control lines (INIT and DONE) are required to configure an FPGA. Data from the PROM is read out sequentially on a single data line (DIN), accessed via the PROM's internal address counter which is incremented on every valid rising edge of CCLK. The serial bit-stream data must be set up at the FPGA's DIN input pin a short time before each rising edge of the FPGA's internally generated CCLK signal.



Typically, a wide range of frequencies can be selected for the FPGA's internally generated CCLK which always starts at a slow default frequency. The FPGA's bitstream contains configuration bits which can switch CCLK to a higher frequency for the remainder of the Master Serial configuration sequence. The desired CCLK frequency is selected during bitstream generation.

Connecting the FPGA device to the configuration PROM for Master Serial Configuration Mode (Figure 8):

- The DATA output of the PROM(s) drive the DIN input of the lead FPGA device.
- The Master FPGA CCLK output drives the CLK input(s) of the PROM(s)
- The CEO output of a PROM drives the CE input of the next PROM in a daisy chain (if any).
- The OE/RESET pins of all PROMs are connected to the INIT_B pins of all FPGA devices. This connection assures that the PROM address counter is reset before the start of any (re)configuration.
- The PROM CE input can be driven from the DONE pin. The CE input of the first (or only) PROM can be driven by the DONE output of all target FPGA devices, provided that DONE is not permanently grounded. CE can also be permanently tied Low, but this keeps the DATA output active and causes an unnecessary I_{CC} active supply current (DC Characteristics Over Operating Conditions).
- The PROM CF pin is typically connected to the FPGA's PROG_B (or PROGRAM) input. For the XCFxxP only, the CF pin is a bidirectional pin. If the XCFxxP CF pin is not connected to the FPGA's PROG_B (or PROGRAM) input, then the pin should be tied High.

FPGA Slave Serial Mode

In Slave Serial mode, the FPGA loads the configuration bit-stream in bit-serial form from external memory synchronized by an externally supplied clock. Upon power-up or reconfiguration, the FPGA's mode select pins are used to select the Slave Serial configuration mode. Slave Serial Mode provides a simple configuration interface. Only a serial data line, a clock line, and two control lines (INIT and DONE) are required to configure an FPGA. Data from the PROM is read out sequentially on a single data line (DIN), accessed via the PROM's internal address counter which is incremented on every valid rising edge of CCLK. The serial bitstream data must be set up at the FPGA's DIN input pin a short time before each rising edge of the externally provided CCLK.

Connecting the FPGA device to the configuration PROM for Slave Serial Configuration Mode (Figure 9):

- The DATA output of the PROM(s) drive the DIN input of the lead FPGA device.
- The PROM CLKOUT (for XCFxxP only) or an external clock source drives the FPGA's CCLK input.

- The CEO output of a PROM drives the CE input of the next PROM in a daisy chain (if any).
- The OE/RESET pins of all PROMs are connected to the INIT_B (or INIT) pins of all FPGA devices. This connection assures that the PROM address counter is reset before the start of any (re)configuration.
- The PROM CE input can be driven from the DONE pin.
 The CE input of the first (or only) PROM can be driven by the DONE output of all target FPGA devices, provided that DONE is not permanently grounded. CE can also be permanently tied Low, but this keeps the DATA output active and causes an unnecessary I_{CC} active supply current (DC Characteristics Over Operating Conditions).
- The PROM CF pin is typically connected to the FPGA's PROG_B (or PROGRAM) input. For the XCFxxP only, the CF pin is a bidirectional pin. If the XCFxxP CF pin is not connected to the FPGA's PROG_B (or PROGRAM) input, then the pin should be tied High.

Serial Daisy Chain

Multiple FPGAs can be daisy-chained for serial configuration from a single source. After a particular FPGA has been configured, the data for the next device is routed internally to the FPGA's DOUT pin. Typically the data on the DOUT pin changes on the falling edge of CCLK, although for some devices the DOUT pin changes on the rising edge of CCLK. Consult the respective device data sheets for detailed information on a particular FPGA device. For clocking the daisy-chained configuration, either the first FPGA in the chain can be set to Master Serial, generating the CCLK, with the remaining devices set to Slave Serial (Figure 10), or all the FPGA devices can be set to Slave Serial and an externally generated clock can be used to drive the FPGA's configuration interface.

FPGA Master SelectMAP (Parallel) Mode⁽¹⁾

In Master SelectMAP mode, byte-wide data is written into the FPGA, typically with a BUSY flag controlling the flow of data, synchronized by the configuration clock (CCLK) generated by the FPGA. Upon power-up or reconfiguration, the FPGA's mode select pins are used to select the Master SelectMAP configuration mode. The configuration interface typically requires a parallel data bus, a clock line, and two control lines (INIT and DONE). In addition, the FPGA's Chip Select, Write, and BUSY pins must be correctly controlled to enable SelectMAP configuration. The configuration data is read from the PROM byte by byte on pins [D0..D7], accessed via the PROM's internal address counter which is incremented on every valid rising edge of CCLK. The bitstream data must be set up at the FPGA's [D0..D7] input

The Master SelectMAP (Parallel) FPGA configuration mode is supported only by the XCFxxP Platform Flash PROM. This mode is not supported by the XCFxxS Platform Flash PROM.



pins a short time before each rising edge of the FPGA's internally generated CCLK signal. If BUSY is asserted (High) by the FPGA, the configuration data must be held until BUSY goes Low. An external data source or external pull-down resistors must be used to enable the FPGA's active Low Chip Select (CS or CS_B) and Write (WRITE or RDWR_B) signals to enable the FPGA's SelectMAP configuration process.

The Master SelectMAP configuration interface is clocked by the FPGA's internal oscillator. Typically, a wide range of frequencies can be selected for the internally generated CCLK which always starts at a slow default frequency. The FPGA's bitstream contains configuration bits which can switch CCLK to a higher frequency for the remainder of the Master SelectMAP configuration sequence. The desired CCLK frequency is selected during bitstream generation.

After configuration, the pins of the SelectMAP port can be used as additional user I/O. Alternatively, the port can be retained using the persist option.

Connecting the FPGA device to the configuration PROM for Master SelectMAP (Parallel) Configuration Mode (Figure 11):

- The DATA outputs of the PROM(s) drive the [D0..D7] input of the lead FPGA device.
- The Master FPGA CCLK output drives the CLK input(s) of the PROM(s)
- The CEO output of a PROM drives the CE input of the next PROM in a daisy chain (if any).
- The OE/RESET pins of all PROMs are connected to the INIT_B pins of all FPGA devices. This connection assures that the PROM address counter is reset before the start of any (re)configuration.
- The PROM CE input can be driven from the DONE pin. The CE input of the first (or only) PROM can be driven by the DONE output of all target FPGA devices, provided that DONE is not permanently grounded. CE can also be permanently tied Low, but this keeps the DATA output active and causes an unnecessary I_{CC} active supply current (DC Characteristics Over Operating Conditions).
- For high-frequency parallel configuration, the BUSY pins of all PROMs are connected to the FPGA's BUSY output. This connection assures that the next data transition for the PROM is delayed until the FPGA is ready for the next configuration data byte.
- The PROM CF pin is typically connected to the FPGA's PROG_B (or PROGRAM) input. For the XCFxxP only, the CF pin is a bidirectional pin. If the XCFxxP CF pin is not connected to the FPGA's PROG_B (or PROGRAM) input, then the pin should be tied High.

FPGA Slave SelectMAP (Parallel) Mode⁽¹⁾

In Slave SelectMAP mode, byte-wide data is written into the FPGA, typically with a BUSY flag controlling the flow of

data, synchronized by an externally supplied configuration clock (CCLK). Upon power-up or reconfiguration, the FPGA's mode select pins are used to select the Slave SelectMAP configuration mode. The configuration interface typically requires a parallel data bus, a clock line, and two control lines (INIT and DONE). In addition, the FPGA's Chip Select, Write, and BUSY pins must be correctly controlled to enable SelectMAP configuration. The configuration data is read from the PROM byte by byte on pins [D0..D7], accessed via the PROM's internal address counter which is incremented on every valid rising edge of CCLK. The bitstream data must be set up at the FPGA's [D0..D7] input pins a short time before each rising edge of the provided CCLK. If BUSY is asserted (High) by the FPGA, the configuration data must be held until BUSY goes Low. An external data source or external pull-down resistors must be used to enable the FPGA's active Low Chip Select (CS or CS_B) and Write (WRITE or RDWR_B) signals to enable the FPGA's SelectMAP configuration process.

After configuration, the pins of the SelectMAP port can be used as additional user I/O. Alternatively, the port can be retained using the persist option.

Connecting the FPGA device to the configuration PROM for Slave SelectMAP (Parallel) Configuration Mode (Figure 12):

- The DATA outputs of the PROM(s) drives the [D0..D7] inputs of the lead FPGA device.
- The PROM CLKOUT (for XCFxxP only) or an external clock source drives the FPGA's CCLK input
- The CEO output of a PROM drives the CE input of the next PROM in a daisy chain (if any).
- The OE/RESET pins of all PROMs are connected to the INIT_B pins of all FPGA devices. This connection assures that the PROM address counter is reset before the start of any (re)configuration.
- The PROM CE input can be driven from the DONE pin. The CE input of the first (or only) PROM can be driven by the DONE output of all target FPGA devices, provided that DONE is not permanently grounded. CE can also be permanently tied Low, but this keeps the DATA output active and causes an unnecessary I_{CC} active supply current (DC Characteristics Over Operating Conditions).
- For high-frequency parallel configuration, the BUSY pins of all PROMs are connected to the FPGA's BUSY output. This connection assures that the next data transition for the PROM is delayed until the FPGA is ready for the next configuration data byte.
- The PROM CF pin is typically connected to the FPGA's

The Slave SelectMAP (Parallel) FPGA configuration mode is supported only by the XCFxxP Platform Flash PROMs. This mode is not supported by the XCFxxS Platform Flash PROM.



PROG_B (or PROGRAM) input. For the XCFxxP only, the CF pin is a bidirectional pin. If the XCFxxP CF pin is not connected to the FPGA's PROG_B (or PROGRAM) input, then the pin should be tied High.

FPGA SelectMAP (Parallel) Device Chaining⁽¹⁾

Multiple Virtex-II FPGAs can be configured using the SelectMAP mode, and be made to start up simultaneously. To configure multiple devices in this way, wire the individual CCLK, DONE, INIT, Data ([D0..D7]), Write (WRITE or RDWR_B), and BUSY pins of all the devices in parallel. If all devices are to be configured with the same bitstream, readback is not being used, and the CCLK frequency selected does not require the use of the BUSY signal, the CS_B pins can be connected to a common line so all of the devices are configured simultaneously (Figure 13).

With additional control logic, the individual devices can be loaded separately by asserting the CS_B pin of each device in turn and then enabling the appropriate configuration data. The PROM can also store the individual bitstreams for each FPGA for SelectMAP configuration in separate design revisions. When design revisioning is utilized, additional control logic can be used to select the appropriate bitstream by asserting the EN_EXT_SEL pin, and using the REV_SEL[1:0] pins to select the required bitstream, while asserting the CS_B pin for the FPGA the bitstream is targeting (Figure 14).

For clocking the parallel configuration chain, either the first FPGA in the chain can be set to Master SelectMAP, generating the CCLK, with the remaining devices set to Slave SelectMAP, or all the FPGA devices can be set to Slave SelectMAP and an externally generated clock can be used to drive the configuration interface. Again, the respective device data sheets should be consulted for detailed information on a particular FPGA device, including which configuration modes are supported by the targeted FPGA device.

Cascading Configuration PROMs

When configuring multiple FPGAs in a serial daisy chain, configuring multiple FPGAs in a SelectMAP parallel chain, or configuring a single FPGA requiring a larger configuration bitstream, cascaded PROMs provide additional memory (Figure 10, Figure 13, Figure 14, and Figure 15). Multiple Platform Flash PROMs can be concatenated by using the CEO output to drive the CE input of the downstream device. The clock signal and the data outputs of all Platform Flash PROMs in the chain are interconnected. After the last data from the first PROM is read, the first PROM asserts its CEO output Low and drives its outputs to

a high-impedance state. The second PROM recognizes the Low level on its $\overline{\text{CE}}$ input and immediately enables its outputs.

After configuration is complete, address counters of all cascaded PROMs are reset if the PROM OE/RESET pin goes Low or CE goes High.

When utilizing the advanced features for the XCFxxP Platform Flash PROM, including the clock output (CLKOUT) option, decompression option, or design revisioning, programming files which span cascaded PROM devices can only be created for cascaded chains containing only XCFxxP PROMs. If the advanced features are not used, then cascaded PROM chains can contain both XCFxxP and XCFxxS PROMs.

Initiating FPGA Configuration

The options for initiating FPGA configuration via the Platform Flash PROM include:

- 1. Automatic configuration on power up
- 2. Applying an external PROG_B (or PROGRAM) pulse
- 3. Applying the JTAG CONFIG instruction

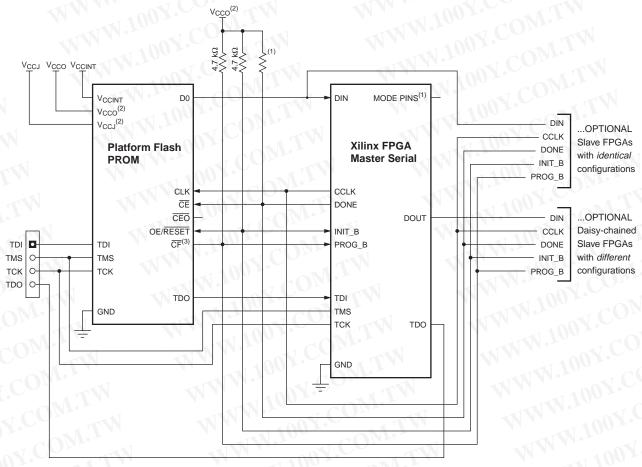
Following the FPGA's power-on sequence or the assertion of the PROG_B (or PROGRAM) pin the FPGA's configuration memory is cleared, the configuration mode is selected, and the FPGA is ready to accept a new configuration bitstream. The FPGA's PROG_B pin can be controlled by an external source, or alternatively, the Platform Flash PROMs incorporate a CF pin that can be tied to the FPGA's PROG_B pin. Executing the CONFIG instruction through JTAG pulses the CF output Low once for 300-500 ns, resetting the FPGA and initiating configuration. The iMPACT software can issue the JTAG CONFIG command to initiate FPGA configuration by setting the "Load FPGA" option.

When using the XCFxxP Platform Flash PROM with design revisioning enabled, the CF pin should always be connected to the PROG_B (or PROGRAM) pin on the FPGA to ensure that the current design revision selection is sampled when the FPGA is reset. The XCFxxP PROM samples the current design revision selection from the external REV_SEL pins or the internal programmable Revision Select bits on the rising edge of CF. When the JTAG CONFIG command is executed, the XCFxxP will sample the new design revision before initiating the FPGA configuration sequence. When using the XCFxxP Platform Flash PROM without design revisioning, if the CF pin is not connected to the FPGA PROG_B (or PROGRAM) pin, then the XCFxxP CF pin should be tied High.

The SelectMAP (Parallel) FPGA configuration modes are supported only by the XCFxxP Platform Flash PROM. These modes are not supported by the XCFxxS Platform Flash PROM.



Configuration PROM to FPGA Device Interface Connection Diagrams

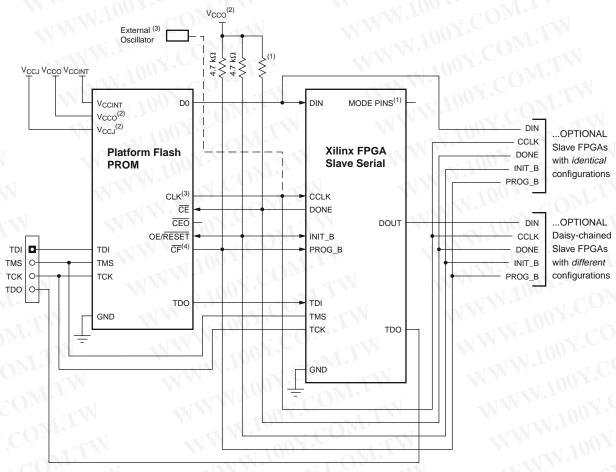


- 1 For Mode pin connections and DONE pin pullup value, refer to the appropriate FPGA data sheet.
- 2 For compatible voltages, refer to the appropriate data sheet.
 3 For the XCFxxS the CF pin is an output pin. For the XCFxxP the CF pin is a bidirectional pin.

ds123_11_100804

Figure 8: Configuring in Master Serial Mode





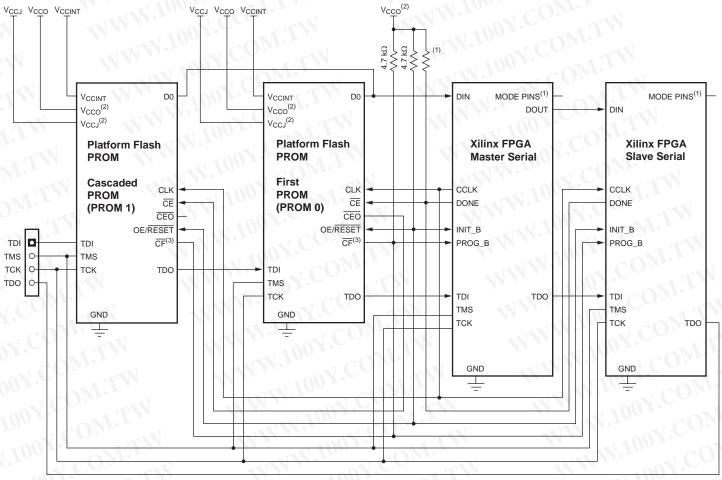
Notes:

- 1 For Mode pin connections and DONE pin pullup value, refer to the appropriate FPGA data sheet.
- 2 For compatible voltages, refer to the appropriate data sheet.
- 3 In Slave Serial mode, the configuration interface can be clocked by an external oscillator, or optionally—for the XCFxxP Platform Flash PROM only—the CLKOUT signal can be used to drive the FPGA's configuration clock (CCLK). If the XCFxxP PROM's CLKOUT signal is used, then it must be tied to a 4.7K\(\Omega\) resistor pulled up to \(\frac{V}{CCO}\).
- 4 For the XCFxxS the \overline{CF} pin is an output pin. For the XCFxxP the \overline{CF} pin is a bidirectional pin.

ds123_12_100804

Figure 9: Configuring in Slave Serial Mode



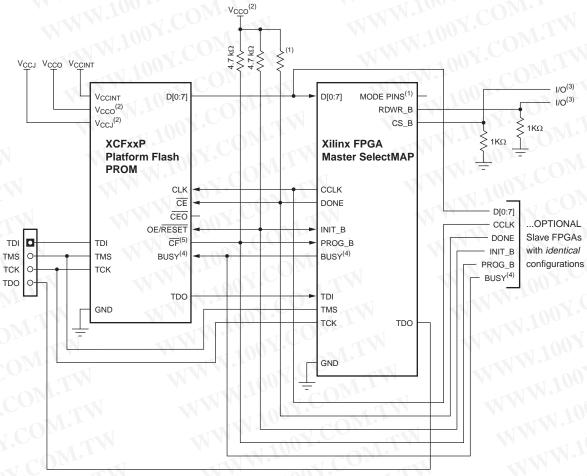


- 1 For Mode pin connections and DONE pin pullup value, refer to the appropriate FPGA data sheet.
- 2 For compatible voltages, refer to the appropriate data sheet.
 3 For the XCFxxP the CF pin is an output pin. For the XCFxxP the CF pin is a bidirectional pin.

ds123_13_100804

Figure 10: Configuring Multiple Devices Master/Slave Serial Mode





Notes:

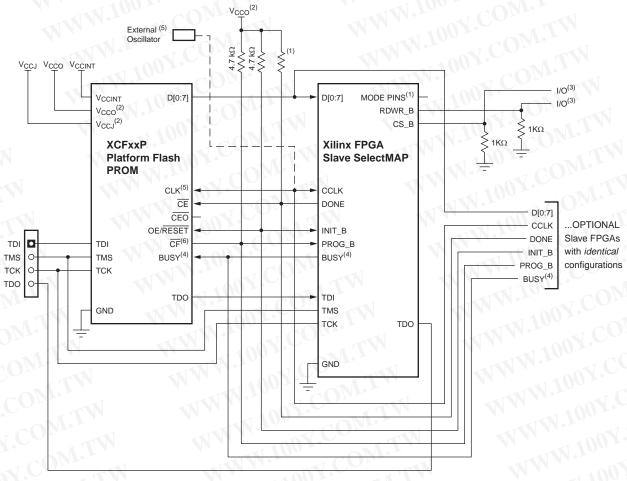
- 1 For Mode pin connections and DONE pin pullup value, refer to the appropriate FPGA data sheet.
- 2 For compatible voltages, refer to the appropriate data sheet.
- CS_B (or CS) and RDWR_B (or WRITE) must be either driven Low or pulled down exernally. One option is shown.

 The BUSY pin is only available with the XCFxxP Platform Flash PROM, and the connection is only required for high-frequency SelectMAP mode configuration. For BUSY pin requirements, refer to the appropriate FPGA data sheet.

5 For the XCFxxP the CF pin is a bidirectional pin.

Figure 11: Configuring in Master SelectMAP Mode





Notes:

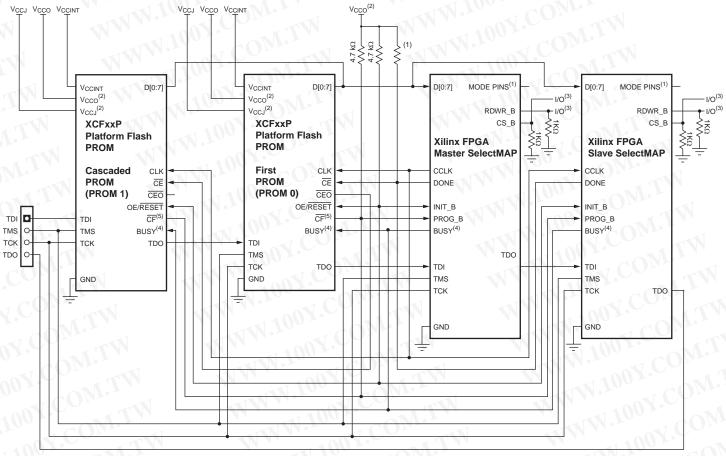
- 1 For Mode pin connections and DONE pin pullup value, refer to the appropriate FPGA data sheet.
- 2 For compatible voltages, refer to the appropriate data sheet.
- 3 CS_B (or $\overline{\text{CS}}$) and RDWR_B (or $\overline{\text{WRITE}}$) must be either driven Low or pulled down exernally. One option is shown.
- 4 The BUSY pin is only available with the XCFxxP Platform Flash PROM, and the connection is only required for high-frequency SelectMAP mode configuration. For BUSY pin requirements, refer to the appropriate FPGA data sheet.
- 5 If the XCFxxP Platform Flash PROM is not used with CLKOUT enabled to drive CCLK, then an external clock is required for Slave SelectMAP (or Slave Parallel) modes. If CLKOUT is used, then it must be tied to a 4.7KΩ resistor pulled up to Voce.
- to V_{CCO}.

 6 For the XCFxxP the $\overline{\text{CF}}$ pin is a bidirectional pin.

ds123_15_100804

Figure 12: Configuring in Slave SelectMAP Mode



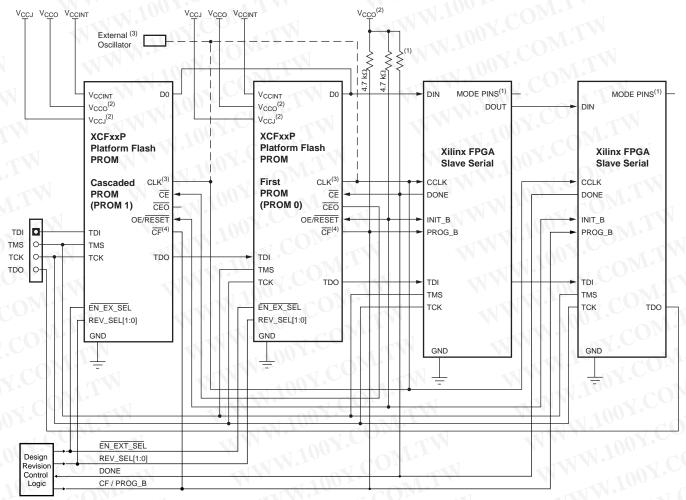


- 1 For Mode pin connections and DONE pin pullup value, refer to the appropriate FPGA data sheet.
- 2 For compatible voltages, refer to the appropriate data sheet.
- 3 CS_B (or CS) and RDWR_B (or WRITE) must be either driven Low or pulled down exernally. One option is shown.
- 4 The BUSY pin is only available with the XCFxxP Platform Flash PROM, and the connection is only required for high-frequency SelectMAP mode configuration. For BUSY pin requirements, refer to the appropriate FPGA data sheet.

5 For the XCFxxP the CF pin is a bidirectional pin.

Figure 13: Configuring Multiple Devices with Identical Patterns in Master/Slave SelectMAP Mode



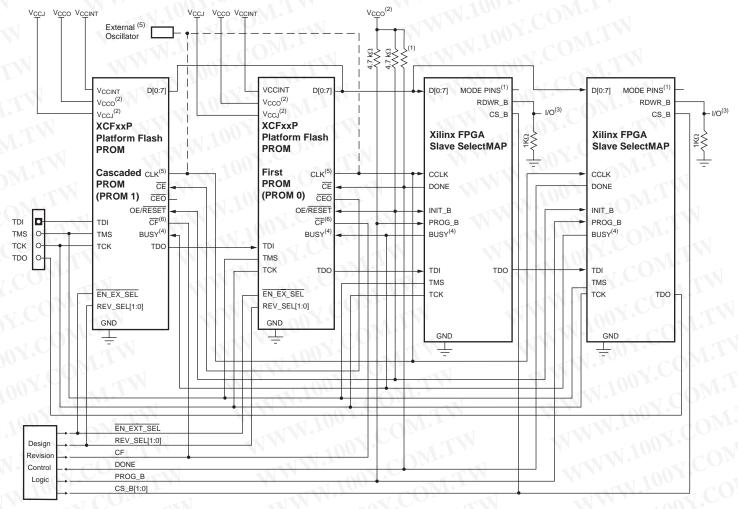


- 1. For Mode pin connections and DONE pin pullup value, refer to the appropriate FPGA data sheet.
- 2 For compatible voltages, refer to the appropriate data sheet.
- 3 In Slave Serial mode, the configuration interface can be clocked by an external oscillator, or optionally the CLKOUT signal can be used to drive the FPGA's configuration clock (CCLK). If the XCFxxP PROM's CLKOUT signal is used, then it must be tied to a 4.7KΩ resistor pulled up to VCCQ.
- $\begin{array}{ccc} & \text{up to V}_{\text{CCO}}. & & \underline{} \\ & \text{4 For the XCFxxP the CF pin is a bidirectional pin.} \end{array}$

ds123_17_100804

Figure 14: Configuring Multiple Devices with Design Revisioning in Slave Serial Mode





Notes:

- 1 For Mode pin connections and DONE pin pullup value, refer to the appropriate FPGA data sheet.
- 2 For compatible voltages, refer to the appropriate data sheet.
- 3 RDWR_B (or WRITE) must be either driven Low or pulled down exernally. One option is shown
- 4 The BUSY pin is only available with the XCFxxP Platform Flash PROM, and the connection is only required for high frequency SelectMAP mode configuration. For BUSY pin requirements, refer to the appropriate FPGA data sheet.
- 5 In Slave SelectMAP mode, the configuration interface can be clocked by an external oscillator, or optionally the CLKOUT signal can be used to drive the FPGA's configuration clock (CCLK). If the XCFxxP PROM's CLKOUT signal is used, then it must be tied to a 4.7KΩ resistor pulled up to VCCO.
- up to VCCO.

 6 For the XCFxxP the $\overline{\text{CF}}$ pin is a bidirectional pin.

ds123_18_100804

Figure 15: Configuring Multiple Devices with Design Revisioning in Slave SelectMAP Mode



Reset and Power-On Reset Activation

At power up, the device requires the V_{CCINT} power supply to monotonically rise to the nominal operating voltage within the specified V_{CCINT} rise time. If the power supply cannot meet this requirement, then the device might not perform power-on reset properly. During the power-up sequence, OE/RESET is held Low by the PROM. Once the required supplies have reached their respective POR (Power On Reset) thresholds, the OE/RESET release is delayed (TOER minimum) to allow more margin for the power supplies to stabilize before initiating configuration. The OE/RESET pin is connected to an external 4.7kΩ pull-up resistor and also to the target FPGA's INIT pin. For systems utilizing slow-rising power supplies, an additional power monitoring circuit can be used to delay the target configuration until the system power reaches minimum operating voltages by holding the OE/RESET pin Low. When OE/RESET is released, the FPGA's INIT pin is pulled High allowing the FPGA's configuration sequence to begin. If the power drops below the power-down threshold (V_{CCPD}), the PROM resets and OE/RESET is again <u>held Low</u> until the after the POR threshold is reached. OE/RESET polarity is not programmable. These power-up requirements are shown graphically in Figure 16.

For a fully powered Platform Flash PROM, a reset occurs whenever OE/RESET is asserted (Low) or CE is deasserted (High). The address counter is reset, CEO is driven High, and the remaining outputs are placed in a high-impedance state.

Notes:

- The XCFxxS PROM only requires V_{CCINT} to rise above its POR threshold before releasing OE/RESET.
- The XCFxxP PROM requires both V_{CCINT} to rise above its POR threshold and for V_{CCO} to reach the recommended operating voltage level before releasing OE/RESET.

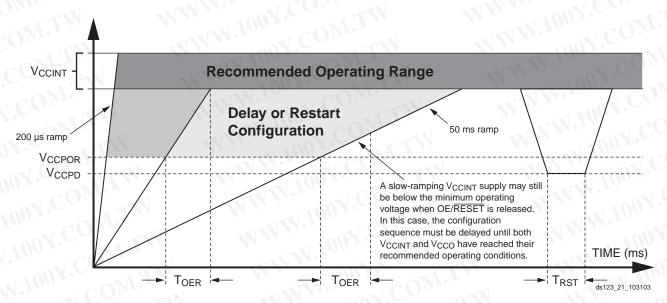


Figure 16: Platform Flash PROM Power-Up Requirements

I/O Input Voltage Tolerance and Power Sequencing

The I/Os on each re-programmable Platform Flash PROM are fully 3.3V-tolerant. This allows 3V CMOS signals to connect directly to the inputs without damage. The core power supply (V_{CCINT}), JTAG pin power supply (V_{CCJ}), output power supply (V_{CCO}), and external 3V CMOS I/O signals can be applied in any order.

Additionally, for the XCFxxS PROM only, when V_{CCO} is supplied at 2.5V or 3.3V and V_{CCINT} is supplied at 3.3V, the I/Os are 5V-tolerant. This allows 5V CMOS signals to connect directly to the inputs on a powered XCFxxS PROM without damage. Failure to power the PROM correctly while supplying a 5V input signal may result in damage to the XCFxxS device.

Standby Mode

The PROM enters a low-power standby mode whenever CE is deasserted (High). In standby mode, the address counter is reset, CEO is driven High, and the remaining outputs are placed in a high-impedance state regardless of the state of the OE/RESET input. For the device to remain in the low-power standby mode, the JTAG pins TMS, TDI, and TDO must not be pulled Low, and TCK must be stopped (High or Low).

When using the FPGA DONE signal to drive the PROM CE pin High to reduce standby power after configuration, an external pull-up resistor should be used. Typically a 330Ω pull-up resistor is used, but refer to the appropriate FPGA data sheet for the recommended DONE pin pull-up value. If the DONE circuit is connected to an LED to indicate FPGA



configuration is complete, and is also connected to the PROM $\overline{\text{CE}}$ pin to enable low-power standby mode, then an external buffer should be used to drive the LED circuit to

ensure valid transitions on the PROM's $\overline{\text{CE}}$ pin. If low-power standby mode is not required for the PROM, then the $\overline{\text{CE}}$ pin should be connected to ground.

Table 9: Truth Table for XCFxxS PROM Control Inputs

Control Inputs		1007.CO TITY	1100X.	Outputs				
OE/RESET	CE	Internal Address	DATA	CEO	ICC			
High Low	1750	If address < TC ⁽²⁾ : increment	Active	High	Active			
High	Low	If address = TC ⁽²⁾ : don't change	High-Z	Low	Reduced			
Low	Low	Held reset	High-Z	High	Active			
X ⁽¹⁾	High	Held reset	High-Z	High	Standby			

Notes:

- X = don't care.
- 2. TC = Terminal Count = highest address value. TC + 1 = address 0.

Table 10: Truth Table for XCFxxP PROM Control Inputs

	Control	Inputs		OOY.CO. TY		Ou	tputs	
OE/RESET	CE	CF	BUSY ⁽⁵⁾	Internal Address	DATA	CEO	CLKOUT	ICC
A'COM	TW		WWW	If address < TC ⁽²⁾ and address < EA ⁽³⁾ : increment	Active	High	Active	Active
High	Low	High	Low	If address < TC ⁽²⁾ and address = EA ⁽³⁾ : don't change	High-Z	High	High-Z	Reduced
001.CO	M.TV	N	WW	Else If address = TC ⁽²⁾ : don't change	High-Z	Low	High-Z	Reduced
High	Low	High	High	Unchanged	Active and Unchanged	High	Active	Active
High	Low	\uparrow	X(1)	Reset ⁽⁴⁾	Active	High	Active	Active
Low	Low	X	X	Held reset ⁽⁴⁾	High-Z	High	High-Z	Active
X	High	X	X	Held reset ⁽⁴⁾	High-Z	High	High-Z	Standby

Notes:

- 1. X = don't care.
- 2. TC = Terminal Count = highest address value. TC + 1 = address 0.
- 3. For the XCFxxP with Design Revisioning enabled, EA = end address (last address in the selected design revision).
- 4. For the XCFxxP with Design Revisioning enabled, Reset = address reset to the beginning address of the selected bank. If Design Revisioning is not enabled, then Reset = address reset to address 0.
- 5. The BUSY input is only enabled when the XCFxxP is programmed for parallel data output and decompression is not enabled.

DC Electrical Characteristics

This data sheet is a Preliminary data sheet. The DC characteristics are based on characterization rather than simulation Further characteristic changes are not expected.

- Absolute Maximum Ratings, page 24
- Supply Voltage Requirements for Power-On Reset and Power-Down, page 24
- •Recommended Operating Conditions, page 25
- Quality and Reliability Characteristics, page 25
- •DC Characteristics Over Operating Conditions, page 26



AC Electrical Characteristics

This data sheet is a Preliminary data sheet. The AC characteristics are based on characterization rather than simulation. Further characteristic changes are not expected.

- •AC Characteristics Over Operating Conditions, page 28
- •AC Characteristics Over Operating Conditions When Cascading, page 32

Absolute Maximum Ratings

Symbol	Description Internal supply voltage relative to GND		XCF01S, XCF02S, XCF04S	XCF08P, XCF16P, XCF32P	Units
V _{CCINT}			-0.5 to +4.0	-0.5 to +2.7	V
V _{CCO}	I/O supply voltage relative to GND		-0.5 to +4.0	-0.5 to +4.0	V
V _{CCJ}	JTAG I/O supply voltage relative to GND		-0.5 to +4.0	-0.5 to +4.0	V
TMO	V _{CCO}		-0.5 to +3.6	-0.5 to +3.6	٧
V _{IN}	Input voltage with respect to GND Vccc	V _{CCO} ≥ 2.5V	-0.5 to +5.5	-0.5 to +3.6	V
$CO_{M_{Pos}}$	0.01	V _{CCO} < 2.5V	-0.5 to +3.6	-0.5 to +3.6	V
V_{TS}	Voltage applied to High-Z output V _{CCO} ≥ 2.5	V _{CCO} ≥ 2.5V	-0.5 to +5.5	-0.5 to +3.6	٧
T _{STG}	Storage temperature (ambient)	001.	-65 to +150	-65 to +150	°C
Tj C	Junction temperature	100 X.Co.	+125	+125	°C

Notes:

- Maximum DC undershoot below GND must be limited to either 0.5V or 10 mA, whichever is easier to achieve. During transitions, the device pins can
 undershoot to -2.0V or overshoot to +7.0V, provided this over- or undershoot lasts less then 10 ns and with the forcing current being limited to
 200 mA.
- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and
 functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to
 Absolute Maximum Ratings conditions for extended periods of time adversely affects device reliability.
- 3. For soldering guidelines, see the information on "Packaging and Thermal Characteristics" at www.xilinx.com.

Supply Voltage Requirements for Power-On Reset and Power-Down

Symbol	CONT.TW WWW.100		, XCF02S, F04S	XCF08P, XCI		
	Description	Min	Max	Min	Max	Units
T _{VCC}	V _{CCINT} rise time from 0V to nominal voltage ⁽²⁾	0.2	50	0.2	50	ms
V _{CCPOR}	POR threshold for the V _{CCINT} supply	1.C		0.5	MAIN	V
T _{OER}	OE/RESET release delay following POR(3)	0.5	3	0.5	30	ms
V _{CCPD}	Power-down threshold for V _{CCINT} supply	700		-	0.5	V
T _{RST}	Time required to trigger a device reset when the V_{CCINT} supply drops below the maximum V_{CCPD} threshold	10	COM	10		ms

Notes:

1. V_{CCINT}, V_{CCO}, and V_{CCJ} supplies may be applied in any order.

At power up, the device requires the V_{CCINT} power supply to monotonically rise to the nominal operating voltage within the specified T_{VCC} rise time. If the power supply cannot meet this requirement, then the device might not perform power-on-reset properly. See <u>Figure</u> 16, page 22.

If the V_{CCINT} and V_{CCO} supplies do not reach their respective recommended operating conditions before the OE/RESET pin is released, then the configuration data from the PROM will not be available at the recommended threshold levels. The configuration sequence must be delayed until both V_{CCINT} and V_{CCO} have reached their recommended operating conditions.



Recommended Operating Conditions

	Description Internal voltage supply		XCF01S	, XCF02S,	XCF04S	XCF08P			
Symbol			Min	Тур	Max	Min	Тур	Max	Units
V _{CCINT}			3.0	3.3	3.6	1.65	1.8	2.0	V
- 1		3.3V Operation	3.0	3.3	3.6	3.0	3.3	3.6	V
	Supply voltage for output drivers	2.5V Operation	2.3	2.5	2.7	2.3	2.5	2.7	V
V_{CCO}		1.8V Operation	1.7	1.8	1.9	1.7	1.8	1.9	V
		1.5V Operation	CG_{Mr}		- 11	TBD	1.5	TBD	V
V _{CCJ}	Supply voltage for JTAG output drivers	3.3V Operation	3.0	3.3	3.6	3.0	3.3	3.6	V
		2.5V Operation	2.3	2.5	2.7	2.3	2.5	2.7	V
	Low-level input voltage	3.3V Operation	0		0.8	0	1007	0.8	V
$O_{M^{-1}}$		2.5V Operation	0 0		0.8	0	-01	0.8	V
V _{IL}		1.8V Operation	00 :	OM	20% V _{CCO}		N.Ton	20% V _{CCO}	V
	TW	1.5V Operation	100-7:0	Time	- I	0	100	TBD	V
COM,	TVN	3.3V Operation	2.0		5.5	2.0		3.6	V
v. c01	High-levelinput	2.5V Operation	1.7	COM.	5.5	1.7	MAIN	3.6	V
V _{IH}	voltage	1.8V Operation	70% V _{CCO}	Wo.	3.6	70% V _{CCO}	-15N.	3.6	V
		1.5V Operation	- 00	V.C.		TBD	111	3.6	V
T _{IN}	Input signal transition time ⁽¹⁾		111-100	CO	500	-		500	ns
Vo	Output voltage		0 10	0 3.	V _{cco}	0		V _{cco}	V
TA	Operating ambient temperature		-40	007-	85	-40	11-11	85	°C

Notes:

Quality and Reliability Characteristics

Symbol	Description	Min	Max	Units
T _{DR}	Data retention	20	W 4.	Years
N _{PE}	Program/erase cycles (Endurance)	20,000		Cycles
V _{ESD}	Electrostatic discharge (ESD)	2,000		Volts

^{1.} Input signal transition time measured between 10% $\rm V_{CCO}$ and 90% $\rm V_{CCO}$.



DC Characteristics Over Operating Conditions

	WWW.100 COM. TW	XCF01S, XCF		S,	XCF08P,		P,	
Symbol	Description	Test Conditions	Min	Max	Test Conditions	Min	Max	Units
	High-level output voltage for 3.3V outputs	I _{OH} = -4 mA	2.4	-T11	$I_{OH} = -4 \text{ mA}$	2.4	N -	V
TW	High-level output voltage for 2.5V outputs	I _{OH} = -500 μA	V _{CCO} – 0.4		I _{OH} = -500 μA	V _{CCO} – 0.4	M	V
V _{OH}	High-level output voltage for 1.8V outputs	I _{OH} = -50 μA	V _{CCO} – 0.4		I _{OH} = -50 μA	V _{CCO} – 0.4	I.M	V
	High-level output voltage for 1.5V outputs	77	-	- 1	I _{OH} = TBD	TBD	7.7	V
T	Low-level output voltage for 3.3V outputs	I _{OL} = 4 mA	-	0.4	I _{OL} = 4 mA	-	0.4	V
V_{OL}	Low-level output voltage for 2.5V outputs	I _{OL} = 500 μA	-	0.4	I _{OL} = 500 μA	CU	0.4	V
	Low-level output voltage for 1.8V outputs	I _{OL} = 50 μA	-	0.4	I _{OL} = 50 μA	V.C	0.4	V
	Low-level output voltage for 1.5V outputs	OM-1	-	-	I _{OL} = TBD	-	TBD	V
I _{CCINT}	Internal voltage supply current, active mode	33 MHz	-	10	33 MHz	07.	10	mA
(J (g)	Output driver supply current, active serial mode	33 MHz	1 -	10	33 MHz	ooy	10	mA
Icco ⁽¹⁾	Output driver supply current, active parallel mode	COMP		-	33 MHz	- 01	40	mA
I _{CCJ}	JTAG supply current, active mode	Note (2)	-	5	Note (2)	700	5	mA
ICCINTS	Internal voltage supply current, standby mode	Note (3)	Lin	5	Note (3)	sī 10	5	mA
Iccos	Output driver supply current, standby mode	Note (3)		1	Note (3)	- 1	11.	mA
I _{CCJS}	JTAG supply current, standby mode	Note (3)		1	Note (3)	15.7	1	mA
liu 100	JTAG pins TMS, TDI, and TDO pull-up current	$V_{CCJ} = max$ $V_{IN} = GND$	Wir	100	$V_{CCJ} = max$ $V_{IN} = GND$	N-N	100	μА
NW.10	Input leakage current	$V_{CCINT} = max$ $V_{CCO} = max$ $V_{IN} = GND \text{ or } V_{CCO}$	-10	10	$V_{CCINT} = max$ $V_{CCO} = max$ $V_{IN} = GND \text{ or } V_{CCO}$	-10	10	μA
I _{IH}	Input and output High-Z leakage current	$V_{CCINT} = max$ $V_{CCO} = max$ $V_{IN} = GND \text{ or } V_{CCO}$	-10	10	$V_{CCINT} = max$ $V_{CCO} = max$ $V_{IN} = GND \text{ or } V_{CCO}$	-10	10	μΑ
I _{ILP}	Source current through internal pull-ups on EN_EXT_SEL, REV_SEL0, REV_SEL1	NWW.10	0 ¹ .	CO.	$V_{CCINT} = max$ $V_{CCO} = max$ $V_{IN} = GND \text{ or } V_{CCO}$	-	100	μА
I _{IHP}	Sink current through internal pull-down on BUSY	WWW.	700 100	0.X.C	$V_{CCINT} = max$ $V_{CCO} = max$ $V_{IN} = GND \text{ or } V_{CCO}$	-100	_1	μА



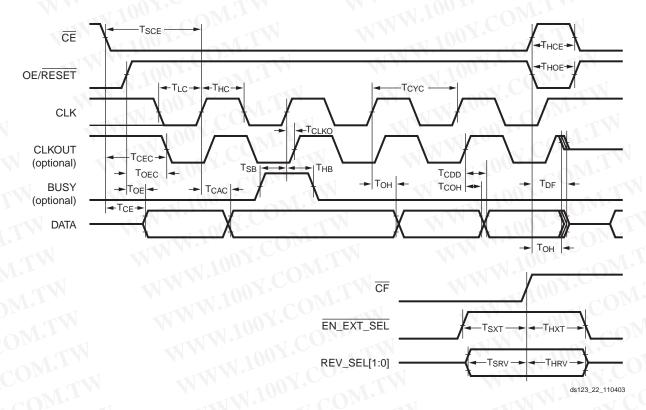
Symbol	WWW.LOOY.COM.TW	XCF01S, XCF	XCF08P, XCF					
	Description	Test Conditions	Min	Max	Test Conditions	Min	Max	Units
C _{IN}	Input capacitance	V _{IN} = GND f = 1.0 MHz	NV	8	V _{IN} = GND f = 1.0 MHz	· T	8	pF
C _{OUT}	Output capacitance	V _{IN} = GND f = 1.0 MHz	NV	14	V _{IN} = GND f = 1.0 MHz	Mr.	14	pF

Notes:

- Output driver supply current specification based on no load conditions.
- TDI/TMS/TCK non-static (active).
- 3. CE High, OE Low, and TMS/TDI/TCK static.



AC Characteristics Over Operating Conditions



OM.TW WWW.100Y.CO					COD
Description	Min	Max	Min	Max	Units
OE/\overline{RESET} to data delay ⁽⁶⁾ when $V_{CCO} = 3.3V$ or 2.5V	$CO_{M^{-1}}$	10	-	25	ns
OE/RESET to data delay ⁽⁶⁾ when V _{CCO} = 1.8V	Mos	30	-	25	ns
$\overline{\text{CE}}$ to data delay ⁽⁵⁾ when V _{CCO} = 3.3V or 2.5V		15	- 1	25	ns
CE to data delay ⁽⁵⁾ when V _{CCO} = 1.8V	A'COD	30	-	25	ns
CLK to data delay ⁽⁷⁾ when V _{CCO} = 3.3V or 2.5V	-170	15	-	25	ns
CLK to data delay ⁽⁷⁾ when V _{CCO} = 1.8V	07.	30	-	25	ns
Data hold from \overline{CE} , OE/\overline{RESET} , or CLK when $V_{CCO} = 3.3V$ or 2.5V	000	OMITY	5	W.W.	ns
Data hold from \overline{CE} , $\overline{OE}/\overline{RESET}$, or CLK when $V_{CCO} = 1.8V$	100	COM.T	5	in in	ns
CE or OE/RESET to data float delay ⁽²⁾ when V _{CCO} = 3.3V or 2.5V	N.100X	25	LAI	45	ns
CE or OE/RESET to data float delay ⁽²⁾ when V _{CCO} = 1.8V	W.100	30	T. I.	45	ns
Clock period ⁽⁷⁾ (serial mode) when $V_{CCO} = 3.3V$ or 2.5V	30	700	25	-	ns
Clock period ⁽⁷⁾ (serial mode) when V _{CCO} = 1.8V	67	007:	25	-	ns
Clock period ⁽⁷⁾ (parallel mode) when $V_{CCO} = 3.3V$ or 2.5V	11 34	any.Cu	30	-	ns
Clock period ⁽⁷⁾ (parallel mode) when V _{CCO} = 1.8V	- T	-V C	30	W -	ns
	$ \begin{array}{c} OE/\overline{RESET} \text{ to data delay}^{(6)} \text{ when } V_{CCO} = 3.3 \text{V or } 2.5 \text{V} \\ \hline OE/\overline{RESET} \text{ to data delay}^{(6)} \text{ when } V_{CCO} = 1.8 \text{V} \\ \hline \overline{CE} \text{ to data delay}^{(5)} \text{ when } V_{CCO} = 3.3 \text{V or } 2.5 \text{V} \\ \hline \overline{CE} \text{ to data delay}^{(5)} \text{ when } V_{CCO} = 1.8 \text{V} \\ \hline CLK \text{ to data delay}^{(7)} \text{ when } V_{CCO} = 3.3 \text{V or } 2.5 \text{V} \\ \hline CLK \text{ to data delay}^{(7)} \text{ when } V_{CCO} = 1.8 \text{V} \\ \hline Data \text{ hold from } \overline{CE}, \text{ OE}/\overline{RESET}, \text{ or } \text{ CLK} \\ \text{when } V_{CCO} = 3.3 \text{V or } 2.5 \text{V} \\ \hline Data \text{ hold from } \overline{CE}, \text{ OE}/\overline{RESET}, \text{ or } \text{ CLK} \\ \text{when } V_{CCO} = 1.8 \text{V} \\ \hline \overline{CE} \text{ or } OE/\overline{RESET} \text{ to data float delay}^{(2)} \\ \text{when } V_{CCO} = 3.3 \text{V or } 2.5 \text{V} \\ \hline \overline{CE} \text{ or } OE/\overline{RESET} \text{ to data float delay}^{(2)} \\ \text{when } V_{CCO} = 1.8 \text{V} \\ \hline Clock \text{ period}^{(7)} \text{ (serial mode) when } V_{CCO} = 3.3 \text{V or } 2.5 \text{V} \\ \hline Clock \text{ period}^{(7)} \text{ (serial mode) when } V_{CCO} = 3.3 \text{V or } 2.5 \text{V} \\ \hline Clock \text{ period}^{(7)} \text{ (parallel mode) when } V_{CCO} = 3.3 \text{V or } 2.5 \text{V} \\ \hline Clock \text{ period}^{(7)} \text{ (parallel mode) when } V_{CCO} = 3.3 \text{V or } 2.5 \text{V} \\ \hline \end{array}$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$



	WWW.TOOX.COM.TW		, XCF02S, F04S	XCF08P, XCF		
Symbol	Description	Min	Max	Min	Max	Units
X]	CLK Low time ⁽³⁾ when V _{CCO} = 3.3V or 2.5V	10	-001	12		ns
Γ _{LC}	CLK Low time ⁽³⁾ when V _{CCO} = 1.8V	15	11.7	12	-31	ns
	CLK High time ⁽³⁾ when V _{CCO} = 3.3V or 2.5V	10	-XX-100	12	13.	ns
Г _{НС}	CLK High time ⁽³⁾ when V _{CCO} = 1.8V	15	- 10	12	WILL	ns
- TW	$\overline{\text{CE}}$ setup time to CLK (guarantees proper counting) ⁽³⁾ when $V_{\text{CCO}} = 3.3 \text{V}$ or 2.5V	20		30	W.TV	ns
r _{sce}	$\overline{\text{CE}}$ setup time to CLK (guarantees proper counting) ⁽³⁾ when $V_{\text{CCO}} = 1.8V$	30		30	OMA	ns
T.Ma	$\overline{\text{CE}}$ hold time (guarantees counters are reset) ⁽⁵⁾ when $V_{\text{CCO}} = 3.3 \text{V}$ or 2.5V	250	MAIN	2000	COM	ns
T _{HCE}	$\overline{\text{CE}}$ hold time (guarantees counters are reset) ⁽⁵⁾ when $V_{\text{CCO}} = 1.8V$	250		2000	COM	ns
TGOM	OE/RESET hold time (guarantees counters are reset) ⁽⁶⁾ when $V_{CCO} = 3.3V$ or 2.5V	250	, and	2000	A COJ	ns
T _{HOE}	OE/RESET hold time (guarantees counters are reset) ⁽⁶⁾ when $V_{CCO} = 1.8V$	250	-	2000	ON-CC	ns
Γ _{SB}	BUSY setup time to CLK when $V_{CCO} = 3.3V$ or 2.5V		-	12		ns
SB	BUSY setup time to CLK when V _{CCO} = 1.8V	1.7-1	-	12	100-7.	ns
. V.C	BUSY hold time to CLK when $V_{CCO} = 3.3V$ or 2.5V	-	-	8	· Your	ns
Гнв	BUSY hold time to CLK when V _{CCO} = 1.8V			8		ns
100 x.	CLK input to CLKOUT output delay when $V_{\rm CCO}$ = 3.3V or 2.5V	OW.I	-	WW	35	ns
1.100 1	CLK input to CLKOUT output delay when $V_{CCO} = 1.8V$	$CO_{M^{-1}}$	-	-111	35	ns
r _{clko}	CLK input to CLKOUT output delay when $V_{CCO} = 3.3V$ or 2.5V with decompression ⁽¹²⁾	I'COM		- 1	35	ns
W.L	CLK input to CLKOUT output delay when $V_{CCO} = 1.8V$ with decompression ⁽¹²⁾	A'COL	TW	- 🔻	35	ns
	$\overline{\text{CE}}$ to CLKOUT delay ⁽⁸⁾ with CLKOUT sourced from internal oscillator, when $V_{\text{CCO}} = 3.3 \text{V}$ or 2.5 V	101-CO	WIL	0	1	μs
	$\overline{\text{CE}}$ to CLKOUT delay ⁽⁸⁾ with CLKOUT sourced from internal oscillator, when $V_{\text{CCO}} = 1.8\text{V}$	100 X.C.	OM.TY	0	1	μs
r _{cec}	CE to CLKOUT delay ⁽⁸⁾ with CLKOUT sourced from external CLK input, when V _{CCO} = 3.3V or 2.5V	100 X	COM.T	0	2 CLK cycles	W.
	CE to CLKOUT delay ⁽⁸⁾ with CLKOUT sourced from external CLK input, when V _{CCO} = 1.8V	N.1003	COM.	0	2 CLK cycles	NI
NN Y	OE/ $\overline{\rm RESET}$ to CLKOUT delay ⁽⁸⁾ with CLKOUT sourced from internal oscillator, when V _{CCO} = 3.3V or 2.5V	W.Inn	A'CON	0	1	μs
T _{OEC}	OE/ $\overline{\rm RESET}$ to CLKOUT delay ⁽⁸⁾ with CLKOUT sourced from internal oscillator, when V _{CCO} = 1.8V	M. I	NOT.CO	0	1	μs
	OE/ $\overline{\rm RESET}$ to CLKOUT delay ⁽⁸⁾ with CLKOUT sourced from external CLK input , when V _{CCO} = 3.3V or 2.5V	W.	1001.Cr	0 1	2 CLK cycles	12
	OE/ $\overline{\rm RESET}$ to CLKOUT delay ⁽⁸⁾ with CLKOUT sourced from external CLK input, when $\rm V_{CCO}$ = 1.8V		1001.0	01.7	2 CLK cycles	-



	WWW.TOOX.COM.TW		5, XCF02S, F04S	XCF08P, XCF		
Symbol	Description	Min	Max	Min	Max	Units
4	CLKOUT to data delay when $V_{CCO} = 3.3V$ or $2.5V^{(9)}$	W-W	-001	Cor	22	ns
T _{CDD}	CLKOUT to data delay when V _{CCO} = 1.8V ⁽⁹⁾	-111	111.700	1 COM	22	ns
T.VI	Data setup time to CLKOUT when $V_{CCO} = 3.3V$ or 2.5V with decompression $^{(9)(12)}$	-	NW-100	5 0	T.T.	ns
T _{DDC}	Data setup time to CLKOUT when $V_{CCO} = 1.8V$ with decompression $^{(9)(12)}$	-	MM.10	500	M	ns
W.T.	Data hold from CLKOUT when V _{CCO} = 3.3V or 2.5V	-	M.M.M.	37.C	DM	ns
Тсон	Data hold from CLKOUT when V _{CCO} = 1.8V	-	WWW.	3 1.	COMP	ns
	Data hold from CLKOUT when $V_{CCO} = 3.3V$ or 2.5V with decompression ⁽¹²⁾	-	WW	301	Cop	ns
	Data hold from CLKOUT when V _{CCO} = 1.8V with decompression ⁽¹²⁾	-	AM	3,00	I.Co.	ns
I.Com	$\overline{\text{EN_EXT_SEL}}$ setup time to $\overline{\text{CF}}$ (rising edge) when $V_{\text{CCO}} = 3.3 \text{V}$ or 2.5 V	IN-	-11/1	300	07.00	ns
T _{SXT}	$\overline{\text{EN_EXT_SEL}}$ setup time to $\overline{\text{CF}}$ (rising edge) when $V_{\text{CCO}} = 1.8V$	T	- 1	300	007	ns
07.00	$\overline{\text{EN_EXT_SEL}}$ hold time from $\overline{\text{CF}}$ (rising edge) when $V_{\text{CCO}} = 3.3 \text{V}$ or 2.5 V	V.T.	-	300	1007	ns
T _{HXT}	$\overline{\text{EN_EXT_SEL}}$ hold time from $\overline{\text{CF}}$ (rising edge) when $V_{\text{CCO}} = 1.8V$	M.	al -	300	1.100	ns
1007.	REV_SEL setup time to $\overline{\text{CF}}$ (rising edge) when $V_{\text{CCO}} = 3.3 \text{V}$ or 2.5 V	OM.	-	300	W.100	ns
T _{SRV}	REV_SEL setup time to \overline{CF} (rising edge) when $V_{CCO} = 1.8V$	COM.	TW-	300	111:10	ns
W.100	REV_SEL hold time from \overline{CF} (rising edge) when $V_{CCO} = 3.3V$ or 2.5V	I'COM	WT	300	111	ns
T _{HRV}	REV_SEL hold time from \overline{CF} (rising edge) when $V_{CCO} = 1.8V$	M.CO	M.T.W	300		ns
WWW	CLKOUT default (fast) frequency ⁽¹⁰⁾	W.Cc	TW	25	50	MHz
F _F	CLKOUT default (fast) frequency with decompression ⁽¹²⁾	ONI.C	OME	12.5	25	MHz



	WWW.IOOY.COM.TW	XCF01S, XCF				
Symbol	Description	Min	Max	Min	Max	Units
-XXI	CLKOUT alternate (slower) frequency ⁽¹¹⁾	11-11	You.	12.5	25	MHz
F _S	CLKOUT alternate (slower) frequency with decompression (12)	WW	1.100	7.C6	12.5	MHz

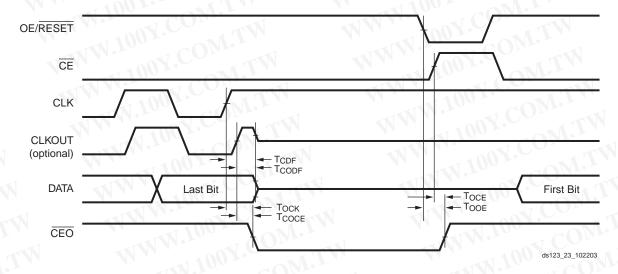
Notes:

- AC test load = 50 pF for XCF01S/XCF02S/XCF04S; 30pF for XCF08P/XCF16P/XCF32P.
- 2. Float delays are measured with 5 pF AC loads. Transition is measured at ±200 mV from steady-state active levels.
- Guaranteed by design, not tested.
- 4 All AC parameters are measured with V_{IL} = 0.0V and V_{IH} = 3.0V.
- If T_{HCE} High < 2 μ s, T_{CE} = 2 μ s. If T_{HOE} Low < 2 μ s, T_{OE} = 2 μ s.
- 6.

- This is the minimum possible T_{CYC} . Actual $T_{CYC} = T_{CAC} + FPGA$ Data setup time. Example: With the XCF32P in serial mode with V_{CCO} at 3.3V, if FPGA Data setup time = 15 ns, then the actual $T_{CYC} = 25$ ns +15 ns = 40 ns. The delay before the enabled CLKOUT signal begins clocking data out of the device is dependent on the clocking configuration. The delay before CLKOUT is enabled will increase if decompression is enabled.
- Slower CLK frequency option may be required to meet the FPGA data sheet setup time.
- Typical CLKOUT default (fast) period = 25 ns (40 MHz)
- Typical CLKOUT alternate (slower) period = 50 ns (20 MHz) 11.
- When decompression is enabled, the CLKOUT signal becomes a controlled clock output. When decompressed data is available, CLKOUT will toggle at ½ the source clock frequency (either ½ the selected internal clock frequency or ½ the external CLKIN frequency). When decompressed data is not available, CLKOUT remains High.



AC Characteristics Over Operating Conditions When Cascading



I.COM	LM MMM.Toox.COM	- 7	, XCF02S, F04S	XCF08P, XCF	~ 7	M.T.	
Symbol	Description	Min	Max	Min	Max	Units	
T _{CDF}	CLK to output float delay ^(2,3) when V _{CCO} = 2.5V or 3.3V	W.	25	WW.	20	ns	
CDF	CLK to output float delay ^(2,3) when V _{CCO} = 1.8V	Mr.	35		20	ns	
DO 1	CLK to $\overline{\text{CEO}}$ delay ^(3,5) when $V_{\text{CCO}} = 2.5 \text{V}$ or 3.3V	ONET	20	-	20	ns	
T _{OCK}	CLK to $\overline{\text{CEO}}$ delay ^(3,5) when V _{CCO} = 1.8V	-117	35	17.14	20	ns	
- 01	$\overline{\text{CE}}$ to $\overline{\text{CEO}}$ delay ^(3,6) when $V_{\text{CCO}} = 2.5 \text{V}$ or 3.3V	CO_{N-1}	20	-111	80	ns	
T _{OCE}	CE to CEO delay ^(3,6) when V _{CCO} = 1.8V	COM	35	1	80	ns	
+1100	OE/\overline{RESET} to \overline{CEO} delay ⁽³⁾ when $V_{CCO} = 2.5V$ or 3.3V	<u></u>	20	-	80	ns	
T _{OOE}	OE/RESET to CEO delay ⁽³⁾ when V _{CCO} = 1.8V	N.C.	35	- 1	80	ns	
N. N.	CLKOUT to $\overline{\text{CEO}}$ delay when $V_{\text{CCO}} = 2.5 \text{V}$ or 3.3V	ov.co		- <	20	ns	
T _{COCE}	CLKOUT to CEO delay when V _{CCO} = 1.8V	×7 C)Nr.	-	20	ns	
T _{CODF}	CLKOUT to output float delay when V _{CCO} = 2.5V or 3.3V	00 x . C	OWIT	N -	25	ns	
JODI	CLKOUT to output float delay when V _{CCO} = 1.8V	Jon	COM		25	ns	

Notes:

- AC test load = 50 pF for XCF01S/XCF02S/XCF04S; 30 pF for XCF08P/XCF16P/XCF32P.
- Float delays are measured with 5 pF AC loads. Transition is measured at ±200 mV from steady state active levels.
- Guaranteed by design, not tested. 3.

- All AC parameters are measured with V_{IL} = 0.0V and V_{IH} = 3.0V. For cascaded PROMs, if the FPGA's dual-purpose configuration data pins are set to persist as configuration pins, the minimum period is increased based on the CLK to CEO and CE to data propagation delays:

 T_{CYC} minimum = T_{OCK} + T_{CE} + FPGA Data setup time.

 T_{CAC} maximum = T_{OCK} + T_{CE}

 For cascaded PROMs, if the FPGA's dual-purpose configuration data pins become general I/O pins after configuration; to allow for the disable to propagate to the cascaded PROMs and to avoid contention on the data lines following configuration, the minimum period is increased based on the CE to CEO and CE to data propagation delays:

 T_{OVC} minimum = T_{CCC} + T_{CC}

 T_{OVC} minimum = T_{CCC} + T_{CC}
 - T_{CYC} minimum = T_{OCE} + T_{CE} T_{CAC} maximum = T_{OCK} + T_{CE}

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Pinouts and Pin Descriptions

The XCFxxS Platform Flash PROM is available in the VO20 and VOG20 packages. The XCFxxP Platform Flash PROM is available in the VO48, VOG48, FS48, and FSG48 packages. This section includes:

- Table 11, XCFxxS Pin Names and Descriptions, page 33
- Figure 17, VO20/VOG20 Pinout Diagram (Top View) with Pin Names, page 34
- Table 12, XCFxxP Pin Names and Descriptions, page 35
- Figure 18, VO48/VOG48 Pinout Diagram (Top View) with Pin Names, page 36
- Table 13, FS48/FSG48 Pin Number/Name Reference, page 38
- Figure 19, FS48/FSG48 Pinout Diagram (Top View), page 38

Notes:

- 1. VO20/VOG20 denotes a 20-pin (TSSOP) Plastic Thin Shrink Small Outline Package
- 2. VO48/VOG48 denotes a 48-pin (TSOP) Plastic Thin Small Outline Package.
- 3. FS48/FSG48 denotes a 48-pin (TFBGA) Plastic Thin Fine Pitch Ball Grid Array (0.8 mm pitch).

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XCFxxS Pinouts and Pin Descriptions

Table 11 provides a list of the pin names and descriptions for the XCFxxS 20-pin VO20/VOG20 package.

Table 11: XCFxxS Pin Names and Descriptions

Pin Name	Boundary Scan Order	Boundary Scan Function	Pin Description	20-pin TSSOP (VO20/VOG20)
D0	4	Data Out	D0 is the DATA output pin to provide data for configuring an FPGA in serial mode. The D0 output is set to a	OW.
DO CON	3	Output Enable	high-impedance state during ISPEN (when not clamped).	DOX.COM
CLK	0	Data In	Configuration Clock Input. Each rising edge on the CLK input increments the internal address counter if the CLK input is selected, $\overline{\text{CE}}$ is Low, and $\overline{\text{OE}/\text{RESET}}$ is High.	100 X COV
1001.	20	Data In	Output Enable/Reset (Open-Drain I/O). When Low, this input	1.100 CO
OE/RESET	19	Data Out	holds the address counter reset and the DATA output is in a high-impedance state. This is a bidirectional open-drain pin	308
	18	Output Enable	that is held Low while the PROM is reset. Polarity is not programmable.	W 100Y.C
CE	15	Data In	Chip Enable Input. When $\overline{\text{CE}}$ is High, the device is put into low-power standby mode, the address counter is reset, and the DATA pins are put in a high-impedance state.	.10
CF 10	22	Data Out	Configuration Pulse (Open-Drain Output). Allows JTAG CONFIG instruction to initiate FPGA configuration without	7.100
WW.1	21	Output Enable	powering down FPGA. This is an open-drain output that is pulsed Low by the JTAG CONFIG command.	WWW.10
CEO	12 CO	Data Out	Chip Enable Output. Chip Enable Output (CEO) is connected to the CE input of the next PROM in the chain. This output is Low when CE is Low and OE/RESET input is High, AND the	12
CEO	V.1011	Output Enable	internal address counter has been incremented beyond its Terminal Count (TC) value. CEO returns to High when OE/RESET goes Low or CE goes High.	WWW
TMS	W.100Y	Mode Select	JTAG Mode Select Input. The state of TMS on the rising edge of TCK determines the state transitions at the Test Access Port (TAP) controller. TMS has an internal 50K Ω resistive pull-up to V _{CCJ} to provide a logic "1" to the device if the pin is not driven.	5
тск	MMN.10	Clock	JTAG Clock Input. This pin is the JTAG test clock. It sequences the TAP controller and all the JTAG test and programming electronics.	6



Table 11: XCFxxS Pin Names and Descriptions (Continued)

Pin Name	Boundary Scan Order	Boundary Scan Function	Pin Description	20-pin TSSOP (VO20/VOG20)
TDI	WWW.	Data In	JTAG Serial Data Input. This pin is the serial input to all JTAG instruction and data registers. TDI has an internal 50K Ω resistive pull-up to V $_{\rm CCJ}$ to provide a logic "1" to the device if the pin is not driven.	W 4
TDO	WW	Data Out	JTAG Serial Data Output. This pin is the serial output for all JTAG instruction and data registers. TDO has an internal $50 K\Omega$ resistive pull-up to V_{CCJ} to provide a logic "1" to the system if the pin is not driven.	17W ₁₇
VCCINT		XW.100	+3.3V Supply. Positive 3.3V supply voltage for internal logic.	18
vcco	1	MM.1007	+3.3V, 2.5V, or 1.8V I/O Supply. Positive 3.3V, 2.5V, or 1.8V supply voltage connected to the output voltage drivers and input buffers.	19
VCCJ	\ -\$I	WWW.100	+3.3V, 2.5V, or 1.8V JTAG I/O Supply. Positive 3.3V, 2.5V, or 1.8V supply voltage connected to the TDO output voltage driver and TCK, TMS, and TDI input buffers.	20
GND	N.	W.10	Ground	011
DNC		MW.	Do not connect. (These pins must be left unconnected.)	2, 9, 12, 14, 15, 16

XCFxxS Pinout Diagram

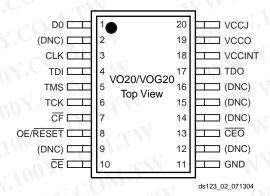


Figure 17: VO20/VOG20 Pinout Diagram (Top View) with Pin Names



XCFxxP Pinouts and Pin Descriptions

Table 12 provides a list of the pin names and descriptions for the XCFxxP 48-pin VO48/VOG48 and 48-pin FS48/FSG48 packages.

Table 12: XCFxxP Pin Names and Descriptions

	Scan Function	Pin Description	TSOP (VO48/ VOG48)	TFBGA (FS48/ FSG48)
28	Data Out	COLL MAN 100X'C	20	H6
27	Output Enable	COM.	0 20	N
26	Data Out	COM.TW	20	H5
25	Output Enable	N.CO. T.TW WW. 100Y	29	113
24	Data Out	ON COM TAN WAY	32	E5
23	Output Enable	D0 is the DATA output pin to provide data for configuring an FPGA in serial mode.	<1 CO)) E3
22	Data Out	D0-D7 are the DATA output pins to provide parallel data for	22	DE
21	Output Enable		33	D5
20	Data Out	(when not clamped).	CV C	OF 1
19	Output Enable	The D1-D7 outputs are set to a high-impedance state during ISPEN (when not clamped) and when serial mode is selected	43	C5
18	Data Out	for configuration. The D1-D7 pins can be left unconnected	7007.	1/4go
17	Output Enable	Whom the Fredhills used in schaimbac.	44	B5
16	Data Out	版 此 上 計 地 000-0 27720170	1.10	1 COR
D6 15	Output Enable	胜特力电子(上海) 86-21-54151736	47	A5
14	Data Out	胜特力电子(深圳) 86-755-83298787 Http://www.100y.com.tw	-110	
13	Output Enable	WWW. OV.CO. TW	48	A6
COM.	Data In	Configuration Clock Input. An internal programmable control bit selects between the internal oscillator and the CLK input pin as the clock source to control the configuration sequence. Each rising edge on the CLK input increments the internal address counter if the CLK input is selected, $\overline{\text{CE}}$ is Low, $\overline{\text{OE}}/\overline{\text{RESET}}$ is High, BUSY is Low (parallel mode only), and $\overline{\text{CF}}$ is High.	12	B3
04	Data In	Output Enable/Reset (Open-Drain I/O).		100
03	Data Out	When Low, this input holds the address counter reset and the DATA and CLKOUT outputs are placed in a high-impedance state. This is a bidirectional open-drain pin that is held Low	11	А3
02	Output Enable	while the PROM is reset. Polarity is not programmable.		
00	Data In	Chip Enable Input. When $\overline{\text{CE}}$ is High, the device is put into low-power standby mode, the address counter is reset, and the DATA and CLKOUT outputs are placed in a high-impedance state.	13	В4
11003	Data In	Configuration Pulse (Open-Drain I/O). As an output, this pin allows the JTAG CONFIG instruction to initiate FPGA configuration without powering down the FPGA. This is an		WW
10	Data Out	open-drain signal that is pulsed Low by the JTAG CONFIG command. As an input, on the rising edge of \overline{CF} , the current	6	D1
09	Output Enable	counter is reset to the start address for the selected revision. If unused, the CF pin should be pulled High using an external		W
	26 25 24 23 22 21 20 19 18 17 16 15 14 13 01 04 03 02 00 11	26 Data Out 25 Output Enable 24 Data Out 23 Output Enable 22 Data Out 21 Output Enable 20 Data Out 19 Output Enable 18 Data Out 17 Output Enable 16 Data Out 15 Output Enable 14 Data Out 13 Output Enable 14 Data Out 10 Data In 01 Data In 01 Data In 01 Data In 01 Data In 02 Output Enable	25 Output Enable 24 Data Out 25 Output Enable 26 Data Out 27 Output Enable 28 Data Out 29 Data Out 20 Data Out 20 Data Out 21 Output Enable 21 Output Enable 22 Data Out 23 Output Enable 25 Data Out 26 Output Enable 27 Output Enable 28 Data Out 28 中方 社 并 \$86-3-5753170 29 Data Out 20 Data In 20 Output Enable 20 Data In 20 Output Enable 21 Data In 20 Output Enable 21 Data In 20 Data In 20 Data In 20 Data In 21 Data In 22 Data Out 25 Data Out 26 Data In 27 Output Enable 28 中方 社 并 \$86-3-5753170 26 Data In 28 中方 社 并 \$86-3-5753170 26 Data In 29 Data In 20 Data In 21 Data In 25 Data In 26 Data In 26 Data In 27 Data In 28 Data In 29 Data In 20 D	26 Data Out 25 Output Enable 24 Data Out 26 Output Enable 27 Data Out 28 Data Out 29 Data Out 29 Data Out 20 Data Out 20 Data Out 21 Output Enable 30 Output Enable 31 Data Out 43 Data Out 44 Data Out 45 Data Out 46 Data Out 47 Output Enable 48 Data Out 40 Data In 41 Data In 42 Data In 44 Data Out 45 Data Out 46 Data In 47 Data In 48 Data Out 48 Data Out 49 Data In 40 Data In 40 Data In 41 Data In 42 Data In 44 Data Out 45 Data Out 46 Data In 47 Data In 48 Data Out 48 Data Out 49 Data In 40 Data In 40 Data In 41 Data In 42 Data In 43 Data Out 44 Data In 45 Data Out 46 Data In 47 Data In 48 Data Out 48 Data Out 49 Data In 40 Data In 40 Data In 41 Data In 42 Data In 43 Data Out 44 Data In 45 Data Out 46 Data In 47 Data In 48 Data Out 48 Data In 49 Data In 40 Data In 40 Data In 41 Data In 42 Data In 43 Data Out 44 Data In 45 Data Out 46 Data In 47 Data In 48 Data Out 48 Data In 49 Data In 40 Data In 40 Data In 41 Data In 42 Data In 43 Data In 44 Data In 45 Data In 46 Data In 47 Data In 48 Data Out 48 Data In 49 Data In 40 Data In 40 Data In 41 Data In 41 Data In 42 Data In 43 Data Out 44 Data In 45 Data Out 46 Data In 47 Data In 48 Data Out 48 Data Out 49 Data In 40 Data In 40 Data In 41 Data In 42 Configuration Pulse (Open-Drain I/O). As an output, this pin allows the JTAG CONFIG instruction to initiate PPGA onfiguration Pulse (Open-Drain I/O). As an output, this pin allows the JTAG CONFIG command. As an input, on the rising edge of CF, the current design revision selection is sampled and the internal address counter ir reset in the start address for



Table 12: XCFxxP Pin Names and Descriptions (Continued)

Pin Name	Boundary Scan Order	Boundary Scan Function	Pin Description	48-pin TSOP (VO48/ VOG48)	48-pin TFBGA (FS48/ FSG48)
CEO	internal address counter has been incremented beyond its		10	D2	
TW	05	Output Enable	internal address counter has been incremented beyond its		N
EN_EXT_SEL	31	Data In	Enable External Selection Input. When this pin is Low, design revision selection is controlled by the Revision Select pins. When this pin is High, design revision selection is controlled by the internal programmable Revision Select control bits.	25	H4
REV_SEL0	30	Data In	Revision Select[1:0] Inputs. When the EN_EXT_SEL is Low, the Revision Select pins are used to select the design revision to be enabled, overriding the internal programmable	26	G3
REV_SEL1	29	Data In	Revision Select control bits. The Revision Select[1:0] inputs have an internal $50 \mathrm{K}\Omega$ resistive pull-up to VCCO to provide a logic "1" to the device if the pins are not driven.	27	G4
BUSY	12	Data In	Busy Input. The BUSY input is enabled when parallel mode is selected for configuration. When BUSY is High, the internal address counter stops incrementing and the current data remains on the data pins. On the first rising edge of CLK after BUSY transitions from High to Low, the data for the next address is driven on the data pins. When serial mode or decompression is enabled during device programming, the BUSY input is disabled. BUSY has an internal $50 \text{K}\Omega$ resistive pull-down to GND to provide a logic "0" to the device if the pin is not driven.	100Y.	
CLKOUT	08	Data Out Output Enable	Configuration Clock Output. An internal Programmable control bit enables the CLKOUT signal, which is sourced from either the internal oscillator or the CLK input pin. Each rising edge of the selected clock source increments the internal address counter if data is available, CE is Low, and OE/RESET is High. Output data is available on the rising edge of CLKOUT. CLKOUT is disabled if CE is High or OE/RESET is Low. If decompression is enabled, CLKOUT is disabled when decompressed data is not ready. When CLKOUT is disabled, the CLKOUT pin is put into a high-Z state. If CLKOUT is used, then it must be pulled High externally using a 4.7K Ω pull-up to $V_{\rm CCO}$.	WWW.	00 Y . 100 Y . 1 C2 Y
TMS	100X.C	Mode Select	JTAG Mode Select Input. The state of TMS on the rising edge of TCK determines the state transitions at the Test Access Port (TAP) controller. TMS has an internal 50K Ω resistive pull-up to V _{CCJ} to provide a logic "1" to the device if the pin is not driven.	21	E2
тск	N.1007	Clock	JTAG Clock Input. This pin is the JTAG test clock. It sequences the TAP controller and all the JTAG test and programming electronics.	20	НЗ
TDI	N. 100	Data In	JTAG Serial Data Input. This pin is the serial input to all JTAG instruction and data registers. TDI has an internal $50 K\Omega$ resistive pull-up to V_{CCJ} to provide a logic "1" to the device if the pin is not driven.	19	G1



Table 12: XCFxxP Pin Names and Descriptions (Continued)

Pin Name	Boundary Scan Order	Boundary Scan Function	Pin Description	48-pin TSOP (VO48/ VOG48)	48-pin TFBGA (FS48/ FSG48)
TDO	WWW	Data Out	JTAG Serial Data Output. This pin is the serial output for all JTAG instruction and data registers. TDO has an internal 50K Ω resistive pull-up to V _{CCJ} to provide a logic "1" to the system if the pin is not driven.	22	E6
VCCINT		W.100	+1.8V Supply. Positive 1.8V supply voltage for internal logic.	4, 15, 34	B1, E1, G6
vcco	W	MN.100	+3.3V, 2.5V, or 1.8V I/O Supply. Positive 3.3V, 2.5V, or 1.8V supply voltage connected to the output voltage drivers and input buffers.	8, 30, 38, 45	B2, C6, D6, G5
VCCJ		WWW.10	+3.3V, 2.5V, or 1.8V JTAG I/O Supply. Positive 3.3V, 2.5V, or 1.8V supply voltage connected to the TDO output voltage driver and TCK, TMS, and TDI input buffers.	24	H2
GND	N W	WWW.	Ground	2, 7, 17, 23, 31, 36, 46	A1, A2, B6, F1, F5, F6, H1
DNC CO	TW LTW	WW	Do Not Connect. (These pins must be left unconnected.)	1, 3, 14, 16, 18, 35, 37, 39, 40, 41, 42	A4, C3, C4, D3, D4, E3, E4, F2, F3, F4, G2

XCFxxP Pinout Diagrams

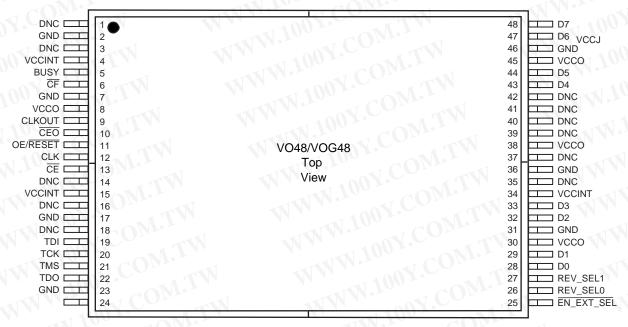


Figure 18: VO48/VOG48 Pinout Diagram (Top View) with Pin Names

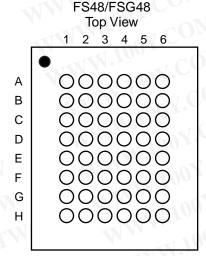


Table 13: FS48/FSG48 Pin Number/Name Reference

Pin Number	Pin Name	Pin Number	Pin Name
A1	GND	E1 .	VCCINT
A2	GND	E2	TMS
A3	OE/RESET	E3	DNC
A4	DNC	E4	DNC
A5	D6	E5	D2
A6	D7	E6	TDO
B1	VCCINT	F1	GND
B2	VCCO	F2	DNC
В3	CLK	F3	DNC
B4	CE	F4	DNC
B5	D5	F5	GND
В6	GND	F6	GND
C1	BUSY	G1	TDI C
C2	CLKOUT	G2	DNC
C3	DNC	G3	REV_SEL0
C4	DNC	G4	REV_SEL1
C5	D4	G5	VCCO
C6	VCCO	G6	VCCINT

Table 13: FS48/FSG48 Pin Number/Name Reference

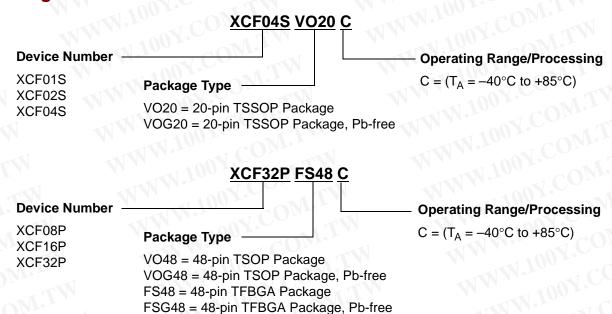
Pin Number	Pin Name	Pin Number	Pin Name
D1	CF	H1	GND
D2	CEO	H2	VCCJ
D3	DNC	Н3	TCK
D4	DNC	H4	EN_EXT_SEL
D5	D3	H5	D1
D6	VCCO	H6	D0



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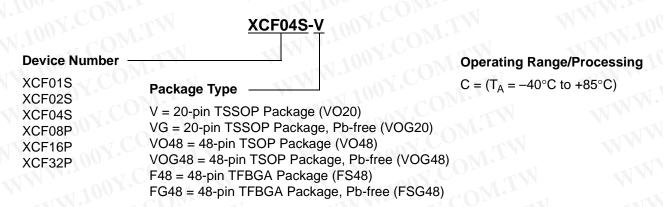
Ordering Information



Valid Ordering Combinations

XCF01SVO20 C	XCF08PVO48 C	XCF08PFS48 C	XCF01SVOG20 C	XCF08PVOG48 C	XCF08PFSG48 C
XCF02SVO20 C	XCF16PVO48 C	XCF16PFS48 C	XCF02SVOG20 C	XCF16PVOG48 C	XCF16PFSG48 C
XCF04SVO20 C	XCF32PVO48 C	XCF32PFS48 C	XCF04SVOG20 C	XCF32PVOG48 C	XCF32PFSG48 C

Marking Information





Revision History

The following table shows the revision history for this document.

Date	Version	Revision
04/29/03	1.0	Xilinx Initial Release.
06/03/03	1.1	Made edits to all pages.
11/05/03	2.0	Major revision.
11/18/03	2.1	Pinout corrections as follows: Table 12: For VO48 package, removed 38 from VCCINT and added it to VCCO. For FS48 package, removed pin D6 from VCCINT and added it to VCCO. Table 13 (FS48 package): For pin D6, changed name from VCCINT to VCCO. For pin A4, changed name from GND to DNC. Figure 18 (VO48 package): For pin 38, changed name from VCCINT to VCCO.
12/15/03	2.2	 Added specification (4.7kΩ) for recommended pull-up resistor on OE/RESET pin to section Reset and Power-On Reset Activation, page 22. Added paragraph to section Standby Mode, page 22, concerning use of a pull-up resistor and/or buffer on the DONE pin.
MMM.100X. MM.100X.COM M.100X.COM M.100X.COM	TW TW M.TW OM.TW COM.TW COM.T COM.T	 limit to itemized features. Section Description, page 1 and following: Added state conditions for CF and BUSY to the descriptive text. Table 2, page 3: Updated Virtex-II configuration bitstream sizes. Section Design Revisioning, page 9: Rewritten. Section PROM to FPGA Configuration Mode and Connections Summary, page 10 and following, five instances: Added instruction to tie CF High if it is not tied to the FPGA's PROG_B (PROGRAM) input. Figure 8, page 14, through Figure 15, page 21: Added footnote indicating the directionality of the CF pin in each configuration. Section I/O Input Voltage Tolerance and Power Sequencing, page 22: Rewritter Table 10, page 23: Added CF column to truth table, and added an additional row to document the Low state of CF. Section Absolute Maximum Ratings, page 24: Revised V_{IN} and V_{TS} for 'P' devices. Section Supply Voltage Requirements for Power-On Reset and Power-Down, page 24:
	1.100X 1.100X 1.100X 1.00X 1.00X	 Revised footnote callout number on T_{OER} from Footnote (4) to Footnote (3). Added Footnote (2) callout to T_{VCC}. Section Recommended Operating Conditions, page 25: Added Typical (Typ) parameter columns and parameters for V_{CCINT} and V_{CCO}/V_{CCJ}. Added 1.5V operation parameter row to V_{IL} and V_{IH}, 'P' devices. Revised V_{IH} Min, 2.5V operation, from 2.0V to 1.7V. Added parameter row T_{IN} and Max parameters (Continued on next page)



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05/07/04 (cont'd)	2.3 (cont'd)	 Section DC Characteristics Over Operating Conditions, page 26: Added parameter row and parameters for parallel configuration mode, 'P' devices, to I_{CCO}. Added Footnote (1) and Footnote (2) with callouts in the Test Conditions column for I_{CCJ}, I_{CCINTS}, I_{CCOS}, and I_{CCJS}, to define active and standby mode requirements. Section AC Characteristics Over Operating Conditions, page 28: Corrected description for second T_{CAC} parameter line to show parameters for 1.8V V_{CCO}. Revised Footnote (7) to indicate V_{CCO} = 3.3V. Applied Footnote (7) to second T_{CYC} parameter line. Section AC Characteristics Over Operating Conditions When Cascading, page 32: Revised Footnote (5)T_{CYC} Min and T_{CAC} Min formulas. Table 12, page 35: Added additional state conditions to CLK description.
OM		- Added function of resetting the internal address counter to \overline{CF} description.
07/20/04	2.4	 Added Pb-free package options VOG20, FSG48, and VOG48. Figure 8, page 14, and Figure 9, page 15: Corrected connection name for FPGA DOUT (OPTIONAL Daisy-chained Slave FPGAs with different configurations) from DOUT to DIN. Section Absolute Maximum Ratings, page 24: Removed parameter T_{SOL} from table. (T_{SOL} information can be found in <i>Package User Guide</i>.) Table 2, page 3: Removed reference to XC2VP125 FPGA.
10/18/04	2.5	Table 1, page 1: Broke out V _{CCO} / V _{CCJ} into two separate columns.
N.100 X.COM	TW TW	 Table 7, page 7: Added clarification of ID code die revision bits. Table 8, page 8: Deleted T_{CKMIN2} (bypass mode) and renamed T_{CKMIN1} to T_{CKMIN}. Table Recommended Operating Conditions, page 25: Separated V_{CCO} and V_{CCO} parameters.
M. 100X.C	M.TW OM.TW	 Table DC Characteristics Over Operating Conditions, page 26: Added most parameter values for XCF08P, XCF16P, XCF32P devices. Added Footnote (1) to I_{CCO} specifying no-load conditions. Table AC Characteristics Over Operating Conditions, page 28: Added most parameter values for XCF08P, XCF16P, XCF32P devices.
	X.COM	 Expanded Footnote (1) to include XCF08P, XCF16P, XCF32P devices. Added Footnote (8) through (11) relating to CLKOUT conditions for various parameters. Added rows to T_{CYC} specifying parameters for parallel mode. Added rows specifying parameters with decompression for T_{CLKO}, T_{COH}, T_{FF}, T_{SF}.
	101.CO	 Added T_{DDC} (setup time with decompression). Table AC Characteristics Over Operating Conditions When Cascading,
	100X.C	 page 32: Added most parameter values for XCF08P, XCF16P, XCF32P devices. Separated Footnote (5) into Footnotes (5) and (6) to specify different derivations of T_{CYC}, depending on whether dual-purpose configuration pins persist as configuration pins, or become general I/O pins after configuration.



	03/14/05 2.6	 Added Virtex-4 LX/FX/SX configuration data to Table 2.
I IN	100	Corrected Virtex-II configuration data in Table 2.
	N NNN	Corrected Virtex-II Pro configuration data in Table 2.
Mir	W.10	Added Spartan-3L configuration data to Table 2.
- 17	M MM.	Added Spartan-3E configuration data to Table 2.
OMr.		Paragraph added to FPGA Master SelectMAP (Parallel) Mode (1), page 11.
MA	In	Changes to DC Characteristics
COMP	TIN WIN.	- T _{OER} changed, page 26.
	C.T.	- I _{OL} changed for V _{OL} , page 26.
CON	WITW WWW	 V_{CCO} added to test conditions for I_{IL}, I_{ILP}, I_{IHP}, and II_H, page 26. Values modified for I_{ILP} and I_{IHP}.
V.CO	WW WITH	Changes to AC Characteristics
- 0(DIVI	- T _{LC} and T _{HC} modified for 1.8V, page 29.
M. C.	TIN N	- New rows added for T _{CEC} and T _{OEC} , page 29.
- - 7 (ON	Minor changes to grammar and punctuation.
00x.	W.I.I.	Add explanation of "Preliminary" to DC and AC Electrical Characteristics.
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